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ELECTRICAL EVALUATION OF RCA MWS5001D RANDOM ACCESS MEMORY

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JUNE 1979

AEROSPACE GROUPS

HUGHES

HUGHES AIRCRAFT COMPANY
CULVER CITY, CALIFORNIA

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AUTHOR(S) A. Klute

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ELECTRICAL EVALUATION OF RCA MWS5001D RANDOM ACCESS MEMORY

Volume 3
FINAL REPORT
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(Appendix B)
Contract Number JPL 954789

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APPENDIX B

QUALIFICATION DATA

INITIAL DATA

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 4

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	105.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	755.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.31NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	25.5UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	100.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	25.9UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	99.5UA	1.00MA

DEVICE PASSED ALL TESTS

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	95.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	80.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	457.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	59.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	432.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	67.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N	60.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	56.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	160.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 90.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	21.7UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-249.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-261.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	273.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	323.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	746.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.16MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	734.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	857.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 5

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	74.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.04NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.48UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	4.49UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	144.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	144.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 5

INITIAL DATA PAGE 2 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	24.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-115.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	232.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	239.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	120.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	121.UA	1.00MA

DEVICE PASSED ALL TESTS

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RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 5

INITIAL DATA PAGE 3 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		155.N		135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		60.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		28.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N		56.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		155.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	<	98.0N	<	92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.74UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-357.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-391.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	368.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	416.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	259.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	296.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	443.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	390.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 6

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		160.N		130.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		30.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	962.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	27.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	99.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	26.9UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	127.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	345.N	<*	185.N		135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	1.00K	<*	44.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		145.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	1.00K	<* <	96.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	346.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	100.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	15.7UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	120.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		160.N		145.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		52.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		28.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		48.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	90.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.14UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-141.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-154.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	153.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	181.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	196.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	256.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	213.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	244.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 7

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.65NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.73NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.28UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	43.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.62UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	51.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	110.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	6.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	34.0N	32.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	962.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	7.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.00NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	45.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.00NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	52.7UA	1.00MA

DEVICE PASSED ALL TESTS

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PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 256 DIAG = 480
FAILED GALPAT (TIGHT LIMIT) ADD = 960 DIAG = 896

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		160.N		150.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		12.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		44.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		155.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N		< 84.0N		< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.83UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-275.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-316.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	299.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	331.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	357.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	331.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	407.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	292.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

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INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	32.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-615.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	769.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	41.6UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	41.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	42.2UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	42.3UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	290.N	<*	155.N		115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	1.00K	<*	34.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	1.00K	<* <	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	577.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	29.5UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	29.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	29.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	29.5UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	150.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	850.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-97.8NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-107.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	109.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	128.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	161.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	153.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	174.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	134.UA	1.00MA

DEVICE PASSED ALL TESTS

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.54NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.86UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	21.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.26UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		115.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	32.0N		30.0N		24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	731.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	656.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	17.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	755.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	19.5UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		145.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.88UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-455.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	448.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	513.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	468.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	407.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	537.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	349.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 10

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	20.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	21.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.54NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.58NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.67UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.78UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.72UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.49UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	130.N	105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	13.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	172.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	187.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	170.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	166.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 90.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.69UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-156.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-178.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	669.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.26UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	121.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	127.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	130.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	98.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 11

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		22.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	18.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	808.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.35UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.20UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	923.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5Ø01D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 11

INITIAL DATA PAGE 2 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		130.N		105.N	250.NS
DATA SETUP TIME	(TDS)	10.ØN		8.ØØN		8.ØØN	50.ØNS
DATA HOLD TIME	(TDH)	14.ØN		10.ØN		20.ØN	50.ØNS
WRITE PULSE WIDTH	(TWP)	38.ØN		34.ØN		32.ØN	90.ØNS
ADDRESS SETUP TIME	(TAS)	58.ØN		28.ØN		22.ØN	70.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN		Ø.ØØ		4.ØØN	60.ØNS
CE TO WRITE TIME	(TWS)	36.ØN		32.ØN		28.ØN	70.ØNS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N		< 80.ØN		< 80.ØN	220.NS
OUTPUT ENABLE TIME	(TEN)	22.ØN		18.ØN		16.ØN	60.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.ØMV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	33.ØNA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-10.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	20.ØNA	500.NA
SUPPLY CURRENT	(ICC1Ø)	6.5ØNA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	8.5ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø)	7.5ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	7.5ØNA	1.ØØMA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 11

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		130.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	893.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-40.7NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	73.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.23UA <*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	8.45UA <*	500.NA
SUPPLY CURRENT	(ICC1B0)	79.6UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	82.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	85.9UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	60.9UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 12

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	95.0N	85.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	40.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	105.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	25.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.23NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.99UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	6.75UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.93UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.12UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	90.0N	80.0N	70.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N	14.0N	14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	42.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	80.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.04NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	8.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	539.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	219.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	28.0NA	1.00MA

DEVICE PASSED ALL TESTS

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N	105.N	100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	50.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	125.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.37UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-206.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-233.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	216.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	247.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	238.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	299.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	271.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	206.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 13

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	20.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	29.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	885.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.18UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.65UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.92UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.86UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		140.N		110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		36.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	54.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		120.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	13.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	11.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.43UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.44UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 13

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 82.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.79UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-157.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-171.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	138.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	167.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	162.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	182.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	179.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	140.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 14

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	145.N	125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	135.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	822.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.41UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	882.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.21UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N		155.N		125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	50.0N		28.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		40.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 113.N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	15.2NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	111.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	13.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	51.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	15.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	56.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 14

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		155.N		140.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		26.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		52.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	<	90.0N	<	86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		32.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.81 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.11UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-146.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-160.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	160.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	188.NA		500.NA
SUPPLY CURRENT	(ICC180)	116.UA		1.00MA
SUPPLY CURRENT	(ICC181)	119.UA		1.00MA
SUPPLY CURRENT	(ICC280)	128.UA		1.00MA
SUPPLY CURRENT	(ICC281)	94.4UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 15

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	95.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	8.00N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	110.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.19NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.52UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.80UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.14UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.87UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N		90.0N		80.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N		6.00N		6.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N		14.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	692.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	44.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	56.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	49.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	46.5NA	1.00MA

DEVICE PASSED ALL TESTS

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	120.N	110.N	100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	42.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	120.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.93UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-233.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-266.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	249.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	291.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	407.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	350.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	469.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	287.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 16

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	155.N	125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N	32.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	40.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	145.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 84.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-462.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	500.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	616.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	664.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	702.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	484.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	315.N	<*	165.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	1.00K	<*	40.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		130.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	1.00K	<*	< 90.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-115.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	654.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	21.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	21.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.5NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 16

INITIAL DATA PAGE 3 OF 3

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 192
FAILED GALPAT (TIGHT LIMIT) ADD = 96 DIAG = 32

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	230.N	185.N	165.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	18.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	34.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	50.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	225.N	180.N	160.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	< 98.0N	< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	880.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-99.2NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-108.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	106.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	122.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	126.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	116.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	141.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	93.2UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 17

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		46.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	542.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	592.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.96UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	6.80UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	145.N	115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	923.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	8.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	5.00NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.60UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.58UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 90.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.14UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-147.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-160.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	163.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	186.NA		500.NA
SUPPLY CURRENT	(ICC180)	105.UA		1.00MA
SUPPLY CURRENT	(ICC181)	104.UA		1.00MA
SUPPLY CURRENT	(ICC280)	124.UA		1.00MA
SUPPLY CURRENT	(ICC281)	88.6UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 18

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		20.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		130.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	27.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.65NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.20UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.49UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.21UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.06UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 18

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	130.N	105.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	346.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	28.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	31.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	28.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	29.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N	60.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	58.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	< 96.0N	< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.61UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-195.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-240.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	224.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	259.NA		500.NA
SUPPLY CURRENT	(ICC180)	148.UA		1.00MA
SUPPLY CURRENT	(ICC181)	164.UA		1.00MA
SUPPLY CURRENT	(ICC280)	154.UA		1.00MA
SUPPLY CURRENT	(ICC281)	122.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 19

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N	145.N	125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	30.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	140.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	< 86.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-538.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	769.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	653.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	640.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	737.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	494.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N	<*	155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	1.00K	<*	36.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	1.00K	<*	90.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	808.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	7.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	20.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	21.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	20.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.5NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 19

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 64 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 576 DIAG = 512

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N	175.N	155.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	30.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	52.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N	170.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	< 94.0N	< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	883.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-133.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-141.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	147.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	170.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	137.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	123.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	155.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	99.7UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 20

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-692.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	692.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	613.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	822.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	685.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	552.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		120.N		100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		24.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	615.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	11.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	12.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	11.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.38UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-94.8NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-108.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	91.4NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	105.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	107.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	116.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	117.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	87.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 21

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		175.N		150.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		54.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		46.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	88.0N	<	82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	38.0N		32.0N		30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	885.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	684.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	769.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	563.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	423.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	250.N		175.N		140.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		48.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		30.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		145.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	<	88.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.00NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.50NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N		200.N		180.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	76.0N		68.0N		62.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		32.0N		32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	74.0N	<*	64.0N		56.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	230.N		200.N		185.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N		< 110.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	46.0N		40.0N		36.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	230.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.28 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.80 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.00UA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-124.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-164.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	128.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	165.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	94.4UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	97.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	99.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	73.5UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 22

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		155.N		135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		32.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		145.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.77NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.77NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.26UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.96UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	391.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	389.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	265.N	<*	155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	1.00K	<*	38.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	1.00K	<*	91.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	53.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	55.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	392.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	392.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	165.N	150.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	28.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	165.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 86.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.64UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-481.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-512.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	507.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	571.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	342.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	289.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	777.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	626.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 23

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	26.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.35NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-8.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	14.3NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	166.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.00UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	12.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 23

INITIAL DATA PAGE 2 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		125.N		105.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	5.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	73.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.86UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	680.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	8.97UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	140.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	150.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 82.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.34UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-312.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-381.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	348.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	574.NA <*	500.NA
SUPPLY CURRENT	(ICC1B0)	309.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	278.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	352.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	233.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 24

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	140.N	115.N	105.N	250.NS
DATA SETUP TIME	(TDS)	8.00N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	34.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	20.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00	4.00N	8.00N	60.0NS
CE TO WRITE TIME	(TWS)	34.0N	30.0N	24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N	110.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	769.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	951.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	15.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.16UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	16.8UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 24

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	110.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	6.00N	4.00N	6.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	32.0N	30.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00	4.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	34.0N	28.0N	20.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	500.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	385.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	10.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	10.9UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	140.N	130.N	250.NS
DATA SETUP TIME	(TDS)	8.00N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	4.00N	8.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	135.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.03UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-116.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-130.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	124.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	140.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	172.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	173.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	197.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	149.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 25

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	125.N	250.NS
DATA SETUP TIME	(TDS)	26.0N	20.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	54.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	88.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.12NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.77UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	17.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.74UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 25

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	34.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.87UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	75.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.37UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 25

INITIAL DATA PAGE 3 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		175.N		160.N	250.NS
DATA SETUP TIME	(TDS)	26.0N		24.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	78.0N		70.0N		64.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		28.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	76.0N	<*	68.0N		60.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		185.N		170.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 116.N		< 108.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	38.0N		32.0N		30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.80 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.35UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-155.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-182.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	169.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	190.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	245.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	371.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	258.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	276.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 26

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		22.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.16UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.55UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.59UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.20UA	1.00MA

DEVICE PASSED ALL TESTS

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		125.N		100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	500.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	231.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	25.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	25.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		46.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.58UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-141.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-156.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	149.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	170.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	211.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	202.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	240.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	162.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 27

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	692.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.29UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	4.31UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.97UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.77UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 27

INITIAL DATA PAGE 2 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		135.N		110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	59.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	60.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	321.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	321.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 27

INITIAL DATA PAGE 3 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 84.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	804.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-118.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-130.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	127.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	148.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	179.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	171.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	147.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	100.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 28

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	140.N	125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	135.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	846.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.11UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.11UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.28UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	795.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 28

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N	150.N	120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	66.0N	32.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	130.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 119.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	500.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	122.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	26.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	124.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	23.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		155.N		145.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		52.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	88.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.18UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-148.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-158.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	163.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	187.NA		500.NA
SUPPLY CURRENT	(ICC180)	177.UA		1.00MA
SUPPLY CURRENT	(ICC181)	163.UA		1.00MA
SUPPLY CURRENT	(ICC280)	199.UA		1.00MA
SUPPLY CURRENT	(ICC281)	131.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 29

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	135.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.04NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	471.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	470.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.04UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	733.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 29

INITIAL DATA PAGE 2 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	135.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	24.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	500.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	448.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	448.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	16.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	17.5NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 29

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 92.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.54UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-302.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-324.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	358.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	407.NA		500.NA
SUPPLY CURRENT	(ICC180)	645.UA		1.00MA
SUPPLY CURRENT	(ICC181)	634.UA		1.00MA
SUPPLY CURRENT	(ICC280)	177.UA		1.00MA
SUPPLY CURRENT	(ICC281)	117.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 30

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	314.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.77NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.0UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.10UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	6.74UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 30

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		115.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		20.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-462.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.58UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.85UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	78.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	85.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	52.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 88.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.54 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.4UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-216.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-228.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	212.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	261.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	319.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	434.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	319.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	307.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 31

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	32.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.77NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-6.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.35UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	23.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.63UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	23.1UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	115.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	32.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N	28.0N	24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	346.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	43.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.00NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 125 C SN: 31

INITIAL DATA PAGE 3 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		140.N		130.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		26.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		145.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.52UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-430.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-469.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	431.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	489.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	365.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	337.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	421.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	288.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 32

INITIAL DATA PAGE 1 OF 3

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 128 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N	180.N	1.00K <*	250.NS
DATA SETUP TIME	(TDS)	22.0N	18.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N	56.0N	62.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	30.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	54.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	205.N	165.N	160.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	< 96.0N	< 102.N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.00NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.15NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	464.NA		1.00MA
SUPPLY CURRENT	(ICC1B1)	478.NA		1.00MA
SUPPLY CURRENT	(ICC2B0)	10.2MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B1)	10.2MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5Ø01Ø 1K CMOS STATIC RAM 2Ø OCT 77 TEMP: -55 C SN: 32

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = Ø
FAILED GALPAT (TIGHT LIMIT) ADD = 128 DIAG = Ø

		VCC = 4.5V		5.ØV		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	315.N	<*	190.N		165.N		250.NS
DATA SETUP TIME	(TDS)	20.ØN		14.ØN		12.ØN		50.ØNS
DATA HOLD TIME	(TDH)	20.ØN		22.ØN		26.ØN		50.ØNS
WRITE PULSE WIDTH	(TWP)	66.ØN		56.ØN		48.ØN		90.ØNS
ADDRESS SETUP TIME	(TAS)	76.ØN	<*	38.ØN		32.ØN		70.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN		Ø.ØØ		4.ØØN		60.ØNS
CE TO WRITE TIME	(TWS)	66.ØN		54.ØN		48.ØN		70.ØNS
MIN READ CYCLE TIME	(TRC)	2ØØ.N		150.N		135.N		250.NS
MIN WRITE CYCLE TIME	(TWC)	< 152.N		< 104.N		< 90.ØN		220.NS
OUTPUT ENABLE TIME	(TEN)	3Ø.ØN		26.ØN		22.ØN		60.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.ØØNA		1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	76.9PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	231.PA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.ØØNA		500.NA
SUPPLY CURRENT	(ICC1Ø)	24.5NA		1.ØØMA
SUPPLY CURRENT	(ICC1Ø1)	25.5NA		1.ØØMA
SUPPLY CURRENT	(ICC2Ø)	10.2MA	<*	1.ØØMA
SUPPLY CURRENT	(ICC2Ø1)	10.2MA	<*	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 128 DIAG = 0

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	250.N		210.N		1.00K	<*	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		16.0N		50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	72.0N		64.0N		1.00K	<*	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		32.0N		36.0N		70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N		60.0NS
CE TO WRITE TIME	(TWS)	72.0N	<*	64.0N		1.00K	<*	70.0NS
MIN READ CYCLE TIME	(TRC)	240.N		215.N		1.00K	<*	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 114.N		< 106.N		1.00K	<*	220.NS
OUTPUT ENABLE TIME	(TEN)	38.0N		34.0N		30.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	200.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.29 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.80 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.00UA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-162.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-183.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	219.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	240.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	87.2UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	85.7UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	9.21MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.19MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 33

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	19.5NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.50NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.62NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	5.72UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.03MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	46.8UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.09MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: -55 C SN: 33

INITIAL DATA PAGE 2 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N		140.N		115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-115.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	346.PA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	2.63UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.00MA		1.00MA
SUPPLY CURRENT	(ICC2B0)	43.8UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.07MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR.

RCA MWS5Ø01D 1K CMOS STATIC RAM 2Ø OCT 77 TEMP: 125 C SN: 33

INITIAL DATA PAGE 3 OF 3

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	175.N	165.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N	58.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	28.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	56.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	165.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 96.0N	< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.31 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.62UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-281.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-308.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	307.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	343.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	192.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.19MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	250.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.21MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 34

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		175.N		150.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	72.0N	<*	58.0N		54.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 129.N		< 112.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	357.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.04NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	156.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	169.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	207.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	208.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N		180.N		150.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	1.00K	<*	68.0N		50.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	1.00K	<* <	115.N	<	92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	231.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	154.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	153.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	197.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	196.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N	<*	220.N		200.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N		60.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	76.0N	<*	72.0N	<*	70.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N		56.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		170.N		155.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 149.N		< 141.N		< 133.N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.0UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-245.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-265.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	250.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	283.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	686.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	942.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	700.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	707.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 20 OCT 77 TEMP: 25 C SN: 35

INITIAL DATA

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	95.0N	90.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	36.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.46NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	1.99UA	1.00MA
SUPPLY CURRENT	(ICC181)	2.57UA	1.00MA
SUPPLY CURRENT	(ICC280)	2.58UA	1.00MA
SUPPLY CURRENT	(ICC281)	1.65UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N	85.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	14.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	38.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	500.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	231.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	13.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	27.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	23.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	15.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N		115.N		110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		52.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		48.0N		44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		135.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N		< 84.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-225.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-239.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	232.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	262.NA		500.NA
SUPPLY CURRENT	(ICC180)	285.UA		1.00MA
SUPPLY CURRENT	(ICC181)	267.UA		1.00MA
SUPPLY CURRENT	(ICC280)	327.UA		1.00MA
SUPPLY CURRENT	(ICC281)	213.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 168-HOUR BURN-IN DATA

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 4

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	130.N	110.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	769.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.08NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	26.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	104.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	27.2UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	103.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PRECEDING PAGE BLANK NOT FILMED

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	100.N	90.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	36.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	37.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	6.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	35.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.40UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	62.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.71UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	71.0UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	100.N	90.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	18.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	17.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	654.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC180)	1.41UA	1.00MA
SUPPLY CURRENT	(ICC181)	60.8UA	1.00MA
SUPPLY CURRENT	(ICC280)	1.06UA	1.00MA
SUPPLY CURRENT	(ICC281)	68.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	140.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		52.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		50.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.93UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-34.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-58.4NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	50.4NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	75.5NA		500.NA
SUPPLY CURRENT	(ICC1B0)	200.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	366.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	192.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	288.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N	58.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	56.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	160.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 90.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	20.7UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-201.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-227.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	253.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	304.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	673.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.05MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	660.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	792.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MW55001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 5

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	73.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.81NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.60UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	5.00UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	169.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	168.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.45UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	640.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	128.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	127.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		135.N		115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		14.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		28.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	29.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	8.58NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	31.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.66UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	720.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	127.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	127.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	135.N	125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	2[illegible].0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 90.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	945.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-52.8NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-65.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	107.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	392.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	46.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	55.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	213.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	206.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	155.N	140.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N	58.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	30.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	56.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	< 98.0N	< 94.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.43UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-315.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-335.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	331.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	379.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	234.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	265.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	425.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	373.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 6

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	160.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	56.0N	38.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	145.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 121.N	99.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	21.9UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	41.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.6UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	43.3UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	310.N	<*	185.N		145.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		10.0N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	22.0N		24.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	112.N	<*	58.0N		36.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		40.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	200.N		140.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 175.N	<	112.N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	15.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	13.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	29.7UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	12.6UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	32.0UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	335.N <*	190.N	145.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	128.N <*	68.0N	38.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	42.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	215.N	145.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 191.N <	122.N <	86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	47.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	11.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	57.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	11.2UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	29.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	11.0UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	30.4UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		155.N		135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		26.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		50.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		28.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		48.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		155.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 146.N	<	88.0N	<	82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	170.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-7.08NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	90.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	49.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	297.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	49.5UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	72.6UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	51.6UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	69.6UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N	160.N	145.N	250.NS
DATA SETUP TIME	(TDS)	12.ØN	12.ØN	16.ØN	50.ØNS
DATA HOLD TIME	(TDH)	22.ØN	26.ØN	28.ØN	50.ØNS
WRITE PULSE WIDTH	(TWP)	64.ØN	56.ØN	52.ØN	90.ØNS
ADDRESS SETUP TIME	(TAS)	36.ØN	30.ØN	30.ØN	70.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN	2.ØØN	6.ØØN	60.ØNS
CE TO WRITE TIME	(TWS)	62.ØN	54.ØN	46.ØN	70.ØNS
MIN READ CYCLE TIME	(TRC)	190.N	160.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	< 96.ØN	< 92.ØN	220.NS
OUTPUT ENABLE TIME	(TEN)	34.ØN	30.ØN	28.ØN	60.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	195.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.11UA	<*	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-121.NA		5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-129.NA		5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	138.NA		5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	164.NA		5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	172.UA		1.ØØMA
SUPPLY CURRENT	(ICC1B1)	192.UA		1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	180.UA		1.ØØMA
SUPPLY CURRENT	(ICC2B1)	168.UA		1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 7

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 576 DIAG = 512

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	115.N	120.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N	30.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	6.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	43.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	56.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.94UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	41.6UA	1.00MA

<** MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	6.00N		6.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	58.0N		30.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	16.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	8.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	950.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	36.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	370.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	42.2UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	135.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	6.00N		6.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	62.0N		30.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	22.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	500.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	22.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	975.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	36.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	405.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	39.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 85 C SN: 7

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	12.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	503.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-29.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-49.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	615.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.63UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	57.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	83.8UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	65.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	83.1UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 32 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	165.N	150.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	12.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	28.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 86.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.92UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-248.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-288.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	283.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	326.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	324.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	309.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	376.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	270.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 8

POST 168 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	54.0N	32.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	7.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	34.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	35.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	36.0UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	35.2UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	260.N	<*	155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	104.N	<*	56.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 155.N	<	98.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	21.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	20.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.9UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	21.3UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	275.N	<*	155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	116.N	<*	64.0N		34.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 167.N		< 112.N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	37.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	9.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	31.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	19.6UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.7UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	20.7UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	19.6UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	145.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-11.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-18.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	128.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	602.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	64.1UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	62.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	67.5UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	60.4UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIOTH	(TWP)	50.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	150.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	896.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-93.7NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-106.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	107.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	128.NA	500.NA
SUPPLY CURRENT	(ICC180)	164.UA	1.00MA
SUPPLY CURRENT	(ICC181)	152.UA	1.00MA
SUPPLY CURRENT	(ICC280)	172.UA	1.00MA
SUPPLY CURRENT	(ICC281)	136.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 9

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		32.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	14.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.62NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	7.20UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	22.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.57UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	82.0N	<*	46.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		28.0N		24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 129.N		< 88.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	654.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.81UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.42UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	17.4UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		125.N		105.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		6.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	84.0N	<*	46.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		30.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 152.N		< 88.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	32.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	7.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	30.5NA	500.NA
SUPPLY CURRENT	(ICC180)	1.91UA	1.00MA
SUPPLY CURRENT	(ICC181)	16.0UA	1.00MA
SUPPLY CURRENT	(ICC280)	1.26UA	1.00MA
SUPPLY CURRENT	(ICC281)	18.3UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 72 DIAG = 8

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		130.N		120.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	262.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-53.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-65.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	359.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.35UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	76.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	84.0UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	88.0UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	76.6UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 40 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	26.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.06UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-388.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-434.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	427.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	715.NA <*	500.NA
SUPPLY CURRENT	(ICC1B0)	420.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	376.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	503.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	349.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 10

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	25.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-423.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.58NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.68UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	5.27UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.18UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.96UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.85NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.36UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	805.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.00UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	700.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	70.0N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	56.0N	30.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 115.N	< 86.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	36.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-10.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	7.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	53.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.33UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	740.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	715.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	600.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		52.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		50.0N		44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		145.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	86.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.78UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-25.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-121.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	845.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.82UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	28.0UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	29.1UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	28.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	22.8UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 10

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	155.N	140.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 94.0N	< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.12UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-196.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-211.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	223.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	256.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	145.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	152.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	156.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	116.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 11

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N	26.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	120.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	19.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.92UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.72UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.60UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.12UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MW5500ID 1K CMOS STATIC RAM 13 DEC 77 TEMP: -40 C SN: 11

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		135.N		110.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	84.0N	<*	44.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 133.N		< 90.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	615.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	850.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	240.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	545.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	250.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		135.N		115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		32.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	96.0N	<*	54.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 145.N		< 96.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	53.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.23NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-37.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	5.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	37.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.20UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	375.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	400.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	155.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.53UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.4NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-139.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	950.NA <*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.92UA <*	500.NA
SUPPLY CURRENT	(ICC1B0)	27.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	28.9UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	29.1UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.1UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		140.N		125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		26.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N		< 82.0N		< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.24UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-106.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-131.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	207.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	545.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	168.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	174.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	192.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	134.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 12

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N	90.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	105.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.3N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	31.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.88NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.89UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.80UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.16UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.19UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	95.0N	80.0N	75.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N	14.0N	14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	42.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	615.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	880.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.50UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.03UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	325.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	95.0N		80.0N		75.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N		14.0N		14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	47.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-346.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-13.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	5.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	31.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.20UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.20UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	885.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	360.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N		100.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.06UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-25.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-107.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	619.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.04UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	36.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	60.9UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	48.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	33.8UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 12

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N		110.N		100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		54.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		0.00	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		50.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		125.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.31UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-192.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-211.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	208.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	246.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	220.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	285.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	254.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	189.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 13

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	31.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.13UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.02UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.24UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.96UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -40 C SN: 13

POST 168 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	200.N		140.N		115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	72.0N	<*	34.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 119.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	16.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	692.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.46NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	11.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	885.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	255.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.09UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.92UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		140.N		115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	88.0N	<*	40.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		120.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 140.N		< 82.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	65.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.27NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-25.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	7.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	35.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	940.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	390.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.84UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.57UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	135.N	120.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	475.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.7NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-60.2NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	46.0NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	234.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	23.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	29.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	30.2UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	25.0UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 15

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 84.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.59UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-134.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-142.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	130.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	162.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	142.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	159.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	156.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	120.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 14

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	145.N	125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	28.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	135.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.92UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.65UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.28UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.35UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		155.N		130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N		36.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 129.N	<	92.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	31.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	955.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	400.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	395.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	370.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		160.N		130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	84.0N	<*	40.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 144.N		< 96.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.35NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-26.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	955.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	445.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	430.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	235.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 85 C SN: 14

POST 168 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		48.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		145.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N		< 82.0N		< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	252.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-14.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-46.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	354.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.38UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	16.5UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	18.4UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	18.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	14.8UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 14

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	160.N	145.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	30.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	160.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 94.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	32.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	195.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.12UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-131.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-142.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	150.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	178.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	104.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	108.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	118.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	84.8UA		1.00MA

<* MEASURED VALJE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 15

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	110.N	95.0N	90.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N	8.00N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	110.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-308.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.50UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.46UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.92UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.16UA	1.00MA

DEVICE PASSED ALL TESTS

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N		90.0N		85.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	34.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	15.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	880.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	535.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	600.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	400.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -55 C SN: 15

POST 168 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	110.N	90.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	6.00N	6.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	36.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.42NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-25.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	915.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	395.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	555.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	390.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N		100.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N		110.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	415.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-22.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-88.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	396.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.39UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	62.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	57.6UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	73.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	43.2UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	120.N	110.N	105.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	42.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.96UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-198.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-226.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	225.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	267.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	356.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	310.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	411.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	254.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 16

POST 168 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 192 DIAG = 128

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	160.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	68.0N	40.0N	34.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N	145.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 123.N	< 94.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	346.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.43UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.01UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.27UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	655.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		170.N		135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	110.N	<*	60.0N		38.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		40.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		130.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 166.N	<	108.N	<	86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	32.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	538.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.85NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	23.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	835.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	215.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	440.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	355.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	300.N	<*	170.N		135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	124.N	<*	66.0N		40.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		130.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 179.N		< 114.N		< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.23NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-22.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	840.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	305.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	480.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	400.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5010 1K CMOS STATIC RAM 13 DEC 77 TEMP: 85 C SN: 16

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 32 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	170.N	150.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	50.0N	36.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	205.N	165.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 111.N	< 92.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.53UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-7.77NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-24.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	270.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.35UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	16.2UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	15.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	18.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	11.4UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MW5500ID 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 16

POST 168 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 32 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N	190.N	170.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	18.0N	24.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	54.0N	40.0N	36.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	50.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	225.N	185.N	160.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 121.N	< 104.N	< 96.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	827.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-82.5NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-93.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	93.1NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	107.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	106.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	97.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	120.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	76.8UA	1.00MA

<** MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 17

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		140.N		120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	50.0NS
CE TO WRITE TIME	(TWS)	52.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.56 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.43UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.00UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.54UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	7.20UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -40 C SN: 17

POST 168 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	145.N	120.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	54.0N	32.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 113.N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	17.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	308.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-5.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	9.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.00UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	320.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.48UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.39UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	145.N	120.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N	36.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 129.N	< 92.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.50 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-19.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	880.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	310.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.15UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.95UA	1.00MA

DEVICE PASSED ALL TESTS

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		140.N		125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		145.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	191.NA		1 00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-15.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-62.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	237.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.42UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	14.0UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	14.1UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	21.7UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	18.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		28.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		52.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		155.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	92.0N	<	86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		32.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.08UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-121.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-131.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	139.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	161.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	88.0UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	87.8UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	108.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	74.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 18

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	48.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	30.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-423.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.24UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.91UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.59UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.27UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	48.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	< 84.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	23.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	955.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	390.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	475.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	275.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	48.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	50.0N	30.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	44.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 115.N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.31NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-25.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.02UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	390.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	300.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	335.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	135.N	120.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	18.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	52.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 90.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	481.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-15.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	91.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	235.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.11UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	21.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	25.6UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	22.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	18.4UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 18

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N	60.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	30.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-10.0N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	66.0N	58.0N	52.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 108.N	< 100.N	< 94.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

QC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.41UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-182.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-189.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	197.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	230.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	128.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	142.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	131.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	104.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 19

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 65 DIAG = 1

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N	150.N	130.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	60.0N	38.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N	< 94.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.48UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.02UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.24UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	840.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N		160.N		130.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	102.N	<*	54.0N		34.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 161.N		< 108.N		< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	20.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	646.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	12.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	900.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	310.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	365.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	205.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	250.N		160.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	108.N	<*	58.0N		36.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 166.N		< 112.N		< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-18.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	925.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	395.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	310.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	240.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		155.N		140.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		32.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		155.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	<	90.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	172.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-20.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-99.8NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	296.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.61UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	17.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	16.1UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	19.9UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	13.2UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 19

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PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 32 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N	175.N	160.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	18.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N	36.0N	34.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	52.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N	175.N	155.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N	< 100.N	< 96.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	810.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-111.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-123.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	126.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	146.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	114.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	101.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	132.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	82.2UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 20

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	120.N	105.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	462.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.52UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.16UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.11UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	800.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	125.N	105.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	52.0N	28.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	110.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	22.5NA	1.00UA
AVERAGE INPUT CUPRENT LOW	(IIL)	269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-5.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.04NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	15.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	920.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	360.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	400.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	300.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		125.N		105.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	62.0N		32.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 116.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.12NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-21.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC180)	665.NA	1.00MA
SUPPLY CURRENT	(ICC181)	235.NA	1.00MA
SUPPLY CURRENT	(ICC280)	420.NA	1.00MA
SUPPLY CURRENT	(ICC281)	295.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 85 C SN: 20

POST 168 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	125.N	115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	36.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	130.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	228.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-11.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-44.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	140.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	924.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	14.2UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	16.7UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	15.9UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	11.8UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5v		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		28.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	86.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.30UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-84.4NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-97.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	83.9NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	100.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	91.4UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	97.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	99.9UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	72.5UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 21

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		175.N		155.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N		48.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 108.N	<	90.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	40.0N		34.0N		30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.52UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.12UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	920.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	600.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		175.N		145.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		48.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	56.0N		34.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		150.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 123.N	<	92.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.59 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	18.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.04NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.04UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	415.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	355.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	235.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N		175.N		145.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		48.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	66.0N		38.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		48.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		145.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 133.N	<	96.0N	<	82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-18.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.92NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.28UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	380.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	510.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	315.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		185.N		165.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		20.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N		56.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		30.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N		54.0N		48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		180.N		165.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	<	96.0N	<	94.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	44.0N		38.0N		34.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	215.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	200.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-16.0NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-68.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	252.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.33UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	12.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	13.6UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	13.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	9.60UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 21

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		200.N		185.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		20.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	76.0N		68.0N		62.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		34.0N		36.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-10.0N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	74.0N	<*	66.0N		56.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	230.N		200.N		185.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 122.N		< 112.N		< 108.N	220.NS
OUTPUT ENABLE TIME	(TEN)	48.0N		40.0N		36.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	240.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.29 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.81 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	990.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-109.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-134.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	118.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	138.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	82.4UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	84.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	86.4UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	63.9UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 15 DEC 77 TEMP: 25 C SN: 22

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N	160.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	60.0N	40.0N	34.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	38.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 114.N	< 88.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	16.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.88NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.58NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.46UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.41UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	435.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	432.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	265.N <*	165.N	135.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	112.N <*	64.0N	38.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	36.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 166.N	< 112.N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	16.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.81NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	8.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	960.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	420.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	432.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	432.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	270.N	<*	160.N		130.N	250.N
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0N
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0N
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		32.0N	90.0N
ADDRESS SETUP TIME	(TAS)	114.N	<*	64.0N		38.0N	70.0N
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0N
CE TO WRITE TIME	(TWS)	42.0N		36.0N		30.0N	70.0N
MIN READ CYCLE TIME	(TRC)	175.N		130.N		110.N	250.N
MIN WRITE CYCLE TIME	(TWC)	< 107.N		< 112.N		< 80.0N	220.N
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0N

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.27NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-24.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.58NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.35UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	635.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	432.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	432.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		28.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N		155.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	243.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-61.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-100.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	512.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.51UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	48.4UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	41.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	480.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	463.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		165.N		150.N	250.N
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0N
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0N
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0N
ADDRESS SETUP TIME	(TAS)	36.0N		32.0N		32.0N	70.0N
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0N
CE TO WRITE TIME	(TWS)	52.0N		46.0N		38.0N	70.0N
MIN READ CYCLE TIME	(TRC)	195.N		165.N		150.N	250.N
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	90.0N	<	88.0N	220.N
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0N

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.51UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-398.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-434.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	425.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	480.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	283.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	245.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	752.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	623.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 23

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		32.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.12NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-8.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	16.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	175.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.37UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.9UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.50UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		135.N		115.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	76.0N	<*	38.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 123.N	<	86.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	538.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	11.2NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	124.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.92UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.24UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.60UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		135.N		115.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	80.0N	<*	42.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 128.N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-346.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-12.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	7.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	75.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.01UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.7UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.09UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.55UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.58 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	584.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-44.2NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-88.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	368.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.60UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	45.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	52.4UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	49.9UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	43.6UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 23

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	140.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	28.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	150.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 84.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.32UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-265.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-301.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	303.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	519.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	263.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	240.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	301.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	200.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 25

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	26.0N	20.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	50.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.56 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	83.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.85NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.26UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	20.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.02UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	16.8UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		18.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		28.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	86.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.50 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	1.05NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	5.65NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	7.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.07UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	590.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	7.68UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -55 C SN: 25

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	135.N	120.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	48.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N	30.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	115.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-7.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC180)	1.20UA	1.00MA
SUPPLY CURRENT	(ICC181)	6.91UA	1.00MA
SUPPLY CURRENT	(ICC280)	685.NA	1.00MA
SUPPLY CURRENT	(ICC281)	7.08UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		160.N		145.N	250.NS
DATA SETUP TIME	(TDS)	28.0N		22.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		60.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		26.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N		58.0N		52.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N		165.N		150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N		< 96.0N		< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		32.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.12UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-21.8NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-55.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	308.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.50UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	49.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	98.1UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	55.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	71.9UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		175.N		160.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		24.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	78.0N		70.0N		64.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		30.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-14.0N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	78.0N	<*	68.0N		60.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		190.N		175.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N		< 110.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	40.0N		34.0N		30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	195.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.81 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.13UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-138.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-155.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	160.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	181.NA		500.NA
SUPPLY CURRENT	(ICC180)	224.UA		1.00MA
SUPPLY CURRENT	(ICC181)	349.UA		1.00MA
SUPPLY CURRENT	(ICC280)	239.UA		1.00MA
SUPPLY CURRENT	(ICC281)	258.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D JK CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 26

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	105.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	120.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.99UA	1.00MA
SUPPLY CUPRENT	(ICC1B1)	2.00UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.15UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.34UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N		32.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 122.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	930.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	275.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	580.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	360.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	80.0N	<*	36.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 132.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	32.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.04NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-14.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.92NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	14.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.07UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	360.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	555.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	240.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		125.N		115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		130.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.40 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	218.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-14.7NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-60.8NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	24.3NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	39.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	28.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	29.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	33.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.4UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5Ø1D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 26

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.ØV		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.ØN		14.ØN		14.ØN	50.ØNS
DATA HOLD TIME	(TDH)	18.ØN		22.ØN		24.ØN	50.ØNS
WRITE PULSE WIDTH	(TWP)	52.ØN		46.ØN		44.ØN	90.ØNS
ADDRESS SETUP TIME	(TAS)	28.ØN		26.ØN		26.ØN	70.ØNS
ADDRESS HOLD TIME	(TAH)	-6.ØØN		Ø.ØØ		4.ØØN	60.ØNS
CE TO WRITE TIME	(TWS)	50.ØN		44.ØN		36.ØN	70.ØNS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.ØN	<	82.ØN	<	80.ØN	220.NS
OUTPUT ENABLE TIME	(TEN)	30.ØN		26.ØN		24.ØN	60.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.50 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.45UA	<*	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-114.NA		5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-136.NA		5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	131.NA		5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	155.NA		5ØØ.NA
SUPPLY CURRENT	(ICC1B0)	174.UA		1.ØØMA
SUPPLY CURRENT	(ICC1B1)	175.UA		1.ØØMA
SUPPLY CURRENT	(ICC2B0)	2Ø4.UA		1.ØØMA
SUPPLY CURRENT	(ICC2B1)	136.UA		1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 27

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		130.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.86UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	4.16UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.67UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.24UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	140.N	120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	8.00N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	58.0N	30.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	120.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	4.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	565.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	915.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	765.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -55 C SN: 27

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		140.N		115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N		34.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 123.N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	28.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.35NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-21.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.77NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	10.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.24UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	405.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	955.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	745.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		140.N		125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	107.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-16.9NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-54.6NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	20.4NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	32.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	33.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	32.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.2UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	15.2UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 27

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		150.N		140.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		28.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		155.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	86.0N	<	86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	755.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-99.1NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-108.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	112.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	136.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	154.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	149.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	129.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	86.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 28

POST 166 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		145.N		125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		30.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.02UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.52UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.60UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	880.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	230.N		155.N		125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	86.0N	<*	42.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 140.N	<	92.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC180)	1.07UA	1.00MA
SUPPLY CURRENT	(ICC181)	280.NA	1.00MA
SUPPLY CURRENT	(ICC280)	565.NA	1.00MA
SUPPLY CURRENT	(ICC281)	255.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		155.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.ØN		10.ØN		12.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	18.ØN		20.ØN		22.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	46.ØN		4Ø.ØN		36.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	98.ØN	<*	52.ØN		32.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN		Ø.ØØ		4.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	44.ØN		38.ØN		32.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		11Ø.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 153.N	<	1Ø2.N	<	8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	26.ØN		22.ØN		2Ø.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	25.5NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	192.PA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.5ØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.5ØNA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.5ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC18Ø)	1.Ø3UA	1.ØØMA
SUPPLY CURRENT	(ICC181)	4ØØ.NA	1.ØØMA
SUPPLY CURRENT	(ICC28Ø)	69Ø.NA	1.ØØMA
SUPPLY CURRENT	(ICC281)	265.NA	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		145.N		130.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		145.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	179.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.0NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-63.7NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	135.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	860.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	25.5UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	24.7UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	29.2UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	19.2UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 28

POST 168 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		160.N		145.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		52.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		28.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		50.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N		< 90.0N		< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.23UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-138.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-150.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	156.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	184.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	160.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	150.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	184.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	118.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 30

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	120.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	301.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.20UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	6.68UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	120.N	105.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	24.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	16.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-11.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.81NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.75UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.52UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	520.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	600.NA	1.00MA

DEVICE PASSED ALL TESTS

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		120.N		100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N		26.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	23.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.77NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	11.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	10.2UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.75UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	575.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	385.NA	1.00MA

DEVICE PASSED ALL TESTS

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		130.N		120.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.44UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-24.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-75.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	825.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.62UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	73.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	110.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	69.1UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	72.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 92.0N	< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.8UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-205.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-231.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	215.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	274.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	316.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	430.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	312.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	304.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 31

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	30.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.58NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.34UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	22.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.15UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	21.6UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -40 C SN: 31

POST 16d HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	78.0N	<*	38.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 126.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	15.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	615.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	11.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.04UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	435.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.2UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		120.N		100.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	80.0N	<*	38.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 128.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-11.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.27UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	12.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	520.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.8UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	125.N	120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	135.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	487.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-56.0NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-94.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	544.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.83UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	54.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	71.4UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	62.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	64.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	130.N	130.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	24.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.55 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.13UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-371.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-406.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	386.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	443.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	523.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	300.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	364.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	254.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 32

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 128 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N <*	195.N	1.00K <*	250.NS
DATA SETUP TIME	(TDS)	24.0N	18.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N	54.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	56.0N	38.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N	56.0N	52.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	215.N	185.N	165.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 133.N	< 102.N	< 96.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.56 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.88NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.70UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.15UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	10.2MA <*	1.00MA
SUPPLY CURRENT	(ICC2B1)	10.2MA <*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 64

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	330.N	<*	210.N		170.N		250.NS
DATA SETUP TIME	(TDS)	22.0N		14.0N		12.0N		50.0NS
DATA HOLD TIME	(TDH)	22.0N		26.0N		28.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N		58.0N		48.0N		90.0NS
ADDRESS SETUP TIME	(TAS)	106.N	<*	56.0N		34.0N		70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N		60.0NS
CE TO WRITE TIME	(TWS)	66.0N		58.0N		50.0N		70.0NS
MIN READ CYCLE TIME	(TRC)	205.N		165.N		150.N		250.NS
MIN WRITE CYCLE TIME	(TWC)	< 183.N		< 123.N		< 92.0N		220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		28.0N		24.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	692.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA		500.NA
AVERAGE INPUT CUPRENT HIGH	(IIH)	1.65NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA		500.NA
SUPPLY CURRENT	(ICC180)	650.NA		1.00MA
SUPPLY CURRENT	(ICC181)	700.NA		1.00MA
SUPPLY CURRENT	(ICC280)	10.2MA	<*	1.00MA
SUPPLY CURRENT	(ICC281)	10.2MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 64

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	1.00K	<*	215.N		165.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		16.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N		60.0N		52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	114.N	<*	64.0N		36.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	72.0N	<*	58.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	215.N		175.N		150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 186.N		< 133.N		< 98.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.59 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	462.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.00NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.08NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	850.NA		1.00MA
SUPPLY CURRENT	(ICC1B1)	800.NA		1.00MA
SUPPLY CURRENT	(ICC2B0)	10.2MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B1)	10.2MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 128 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N	195.N	1.00K <*	250.NS
DATA SETUP TIME	(TDS)	24.0N	20.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N	56.0N	1.00K <*	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	30.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N	56.0N	1.00K <*	70.0NS
MIN READ CYCLE TIME	(TRC)	250.N	200.N	1.00K <*	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 116.N	< 96.0N	1.00K <*	220.NS
OUTPUT ENABLE TIME	(TEN)	38.0N	32.0N	30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	184.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-18.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-84.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	451.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.32UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	10.5UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	10.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	9.68MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.69MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 32

POST 168 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 96 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 128 DIAG = 0

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		205.N		1.00K	<*	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		16.0N		50.0NS
DATA HOLD TIME	(TDH)	22.0N		26.0N		30.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	72.0N		64.0N		1.00K	<*	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		34.0N		36.0N		70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		4.00N		60.0NS
CE TO WRITE TIME	(TWS)	74.0N	<*	64.0N		1.00K	<*	70.0NS
MIN READ CYCLE TIME	(TRC)	245.N		215.N		1.00K	<*	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N		< 108.N		1.00K	<*	220.NS
OUTPUT ENABLE TIME	(TEN)	40.0N		34.0N		30.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	210.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	773.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-118.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-128.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	167.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	182.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	65.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	64.0UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	9.28MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.25MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 35

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		165.N		145.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N		24.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	24.0NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-423.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.35NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	6.81UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.51MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	47.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.52MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIM
ADDRESS ACCESS TIME	(TAA)	220.N		165.N		140.N	25Ø
DATA SETUP TIME	(TDS)	16.ØN		14.ØN		10.ØN	5Ø.
DATA HOLD TIME	(TDH)	18.ØN		18.ØN		22.ØN	5Ø.
WRITE PULSE WIDTH	(TWP)	54.ØN		4Ø.ØN		4Ø.ØN	9Ø.
ADDRESS SETUP TIME	(TAS)	52.ØN		3Ø.ØN		24.ØN	7Ø.
ADDRESS HOLD TIME	(TAH)	-6.ØØN		-2.ØØN		2.ØØN	6Ø.
CE TO WRITE TIME	(TWS)	54.ØN		44.ØN		38.ØN	7Ø.
MIN READ CYCLE TIME	(TRC)	155.N		12Ø.N		1Ø5.N	25Ø
MIN WRITE CYCLE TIME	(TWC)	< 115.N	<	8Ø.ØN	<	8Ø.ØN	22Ø
OUTPUT ENABLE TIME	(TEN)	28.ØN		24.ØN		22.ØN	6Ø.

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV		4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.4Ø V		3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.9Ø V		4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	15.5NA		1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA		5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.5ØNA		5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.Ø4NA		5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.5ØNA		5ØØ.NA
SUPPLY CURRENT	(ICC18Ø)	3.97UA		1.ØØMA
SUPPLY CURRENT	(ICC181)	1.56MA	<*	1.ØØMA
SUPPLY CURRENT	(ICC28Ø)	44.8UA		1.ØØMA
SUPPLY CURRENT	(ICC281)	1.6ØMA	<*	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		165.N		135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N		36.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 153.N	<	90.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	10.0MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	15.0MV	<*	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	15.0MV	<*	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.50NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.81NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA		500.NA
SUPPLY CURRENT	(ICC180)	4.06UA		1.00MA
SUPPLY CURRENT	(ICC181)	1.58MA	<*	1.00MA
SUPPLY CURRENT	(ICC280)	44.7UA		1.00MA
SUPPLY CURRENT	(ICC281)	1.61MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 13 DEC 77 TEMP: 65 C SN: 33

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N	190.N	170.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	52.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	150.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 88.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.26UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-37.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-81.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	155.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	870.NA	<*	500.NA
SUPPLY CURRENT	(ICC180)	30.0UA		1.00MA
SUPPLY CURRENT	(ICC181)	1.39MA	<*	1.00MA
SUPPLY CURRENT	(ICC280)	73.6UA		1.00MA
SUPPLY CURRENT	(ICC281)	1.46MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 33

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	270.N	<*	235.N		215.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N		58.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		30.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-10.0N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N		56.0N		48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		165.N		150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N		< 98.0N		< 94.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		32.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.26UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-220.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-236.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	245.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	278.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	156.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.41MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	208.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.50MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 34

POST 16H HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		175.N		155.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	86.0N	<*	68.0N		64.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 144.N		< 122.N		< 114.N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.58 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	353.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.88NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	150.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	163.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	192.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	194.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		180.N		155.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	108.N	<*	76.0N	<*	60.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 163.N		< 123.N		< 108.N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	15.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	692.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	144.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	144.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	183.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	184.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	250.N		185.N		155.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	120.N	<*	82.0N	<*	64.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 174.N		< 129.N		< 106.N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	15.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	615.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	145.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	144.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	183.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	183.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		185.N		170.N		250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N		50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		52.0N		48.0N		90.0NS
ADDRESS SETUP TIME	(TAS)	82.0N	<*	76.0N	<*	74.0N	<*	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N		60.0NS
CE TO WRITE TIME	(TWS)	56.0N		50.0N		44.0N		70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		145.N		135.N		250.NS
MIN WRITE CYCLE TIME	(TWC)	< 149.N		< 137.N		< 132.N		220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.28UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-53.6NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-39.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	195.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	979.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	260.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	546.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	303.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	304.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	260.N	<*	220.N		205.N		250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		18.0N		50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		60.0N		56.0N		90.0NS
ADDRESS SETUP TIME	(TAS)	82.0N	<*	80.0N	<*	80.0N	<*	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N		60.0NS
CE TO WRITE TIME	(TWS)	64.0N		58.0N		50.0N		70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		170.N		155.N		250.NS
MIN WRITE CYCLE TIME	(TWC)	< 157.N		< 149.N		< 145.N		220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		28.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.8UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-223.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-236.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	243.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	283.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	636.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	880.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	652.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	656.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 25 C SN: 35

POST 168 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	110.N		100.N		90.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		38.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.50 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	15.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.77UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.06UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.10UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.77UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -40 C SN: 35

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	90.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	500.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1R0)	980.NA	1.00MA
SUPPLY CURRENT	(ICC1R1)	310.NA	1.00MA
SUPPLY CURRENT	(ICC2R0)	555.NA	1.00MA
SUPPLY CURRENT	(ICC2R1)	360.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: -55 C SN: 35

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	90.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	21.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.46NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	8.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.36UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	410.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	600.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	300.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N	105.N	100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	120.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.07UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-57.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-437.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	280.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.58UA	<*	500.NA
SUPPLY CURRENT	(ICC180)	43.2UA		1.00MA
SUPPLY CURRENT	(ICC181)	44.3UA		1.00MA
SUPPLY CURRENT	(ICC280)	51.3UA		1.00MA
SUPPLY CURRENT	(ICC281)	32.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 13 DEC 77 TEMP: 125 C SN: 35

POST 168 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	115.N	110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	52.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	48.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	135.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 86.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

QC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.02UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-206.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-225.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	260.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	740.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	260.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	245.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	302.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	192.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 1000-HOUR BURN-IN DATA

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 4

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	130.N		105.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	749.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	25.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	102.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	25.8UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	102.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PRECEDING PAGE BLANK NOT FILMED

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 4

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	100.N	85.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	25.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.04UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	60.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.04UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	69.6UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N		95.0N		85.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.58NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	427.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	59.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	410.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	68.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	140.N	120.N	110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	54.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	48.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	135.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.48UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.4NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-56.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	134.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	535.NA <*	500.NA
SUPPLY CURRENT	(ICC1B0)	220.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	404.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	218.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	515.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIM
ADDRESS ACCESS TIME	(TAA)	170.N		145.N		130.N	250
DATA SETUP TIME	(TDS)	20.0N		18.0N		18.0N	50.
DATA HOLD TIME	(TDH)	14.0N		18.0N		30.0N	50.
WRITE PULSE WIDTH	(TWP)	66.0N		60.0N		54.0N	90.
ADDRESS SETUP TIME	(TAS)	22.0N		22.0N		22.0N	70.
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		0.00	60.
CE TO WRITE TIME	(TWS)	62.0N		54.0N		48.0N	70.
MIN READ CYCLE TIME	(TRC)	180.N		160.N		145.N	250
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	<	92.0N	<	86.0N	220
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	22.6UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-251.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-264.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	287.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	337.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	755.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.18MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	741.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	866.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR.

RCA MW55001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: S

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	69.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.58NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC180)	3.25UA	1.00MA
SUPPLY CURRENT	(ICC181)	4.22UA	1.00MA
SUPPLY CURRENT	(ICC280)	147.UA	1.00MA
SUPPLY CURRENT	(ICC281)	147.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 5

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		14.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		22.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	301.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	319.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	126.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	124.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 5

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.46NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	229.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	242.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	121.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	120.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		50.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N		< 88.0N		< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.57UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-62.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-109.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	123.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	537.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	46.5UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	56.4UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	209.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	202.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N	58.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	< 96.0N	< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.70UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-329.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-353.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	348.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	397.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	241.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	276.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	429.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	379.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 6

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		160.N		135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		32.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		40.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		145.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	<	88.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.7UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	26.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	16.7UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	26.1UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5Ø01D 1K CMOS STATIC RAM Ø9 FEB 78 TEMP: -4Ø C SN: 6

POST 1ØØØ HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	325.N <*	185.N	135.N	25Ø.NS
DATA SETUP TIME	(TDS)	14.ØN	8.ØØN	1Ø.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	22.ØN	24.ØN	28.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	5Ø.ØN	42.ØN	36.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	88.ØN <*	4Ø.ØN	3Ø.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN	2.ØØN	6.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	46.ØN	36.ØN	3Ø.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	2ØØ.N	14Ø.N	115.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 148.N	< 92.ØN	< 8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	26.ØN	22.ØN	2Ø.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	13Ø.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.4Ø V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	5.5ØNA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	654.PA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.5ØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.ØØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1B0)	8.66UA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	15.ØUA	1.ØØMA
SUPPLY CURRENT	(ICC2B0)	8.82UA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	16.6UA	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	1.00K <*	190.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	42.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	116.N <*	46.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	215.N	145.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 175.N	< 98.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	7.14UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.15UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.6UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 85 C SN: 6

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	155.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	52.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	26.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	48.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	155.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 88.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.98UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-25.2NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-165.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	725.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.48UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	47.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	59.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	50.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	52.8UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 6

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		160.N		145.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		58.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		28.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N		54.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	<	96.0N	<	92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	195.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.28UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-142.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-151.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	162.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	189.NA		500.NA
SUPPLY CURRENT	(ICC180)	184.UA		1.00MA
SUPPLY CURRENT	(ICC181)	196.UA		1.00MA
SUPPLY CURRENT	(ICC280)	201.UA		1.00MA
SUPPLY CURRENT	(ICC281)	161.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 7

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	0.00 A	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.02UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	25.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.33UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	26.8UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 7

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	115.N	100.N	250.NS
DATA SETUP TIME	(TDS)	6.00N	6.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N	28.0N	24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	13.0NA	1.00MA
SUPPLY CURRENT	(ICC181)	19.4UA	1.00MA
SUPPLY CURRENT	(ICC280)	12.0NA	1.00MA
SUPPLY CURRENT	(ICC281)	20.9UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	110.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	6.00N	6.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	32.0N	32.0N	24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.46NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	17.6UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.50NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	19.3UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	140.N	130.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.35UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-107.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-877.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	306.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.41UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	61.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	79.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	71.1UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	73.2UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 7

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	160.N	150.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	12.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 84.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.09UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-291.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-334.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	321.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	348.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	364.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	331.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	416.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	285.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 8

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		135.N		115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		130.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	385.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.4UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	16.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	16.3UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	270.N	<*	150.N		115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	72.0N	<*	32.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 123.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	6.76UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	6.83UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.76UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	6.89UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 8

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	280.N	<*	155.N		115.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	88.0N	<*	36.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 140.N		< 84.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.60UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	5.50UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.55UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.47UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.09UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-36.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-142.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	797.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.45UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	43.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	43.3UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	46.2UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	40.5UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 8

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	150.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	939.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-100.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-114.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	116.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	134.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	142.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	137.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	154.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	114.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 9

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		10.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		30.0N		24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.38NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.88NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	6.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	19.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.82UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 9

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		125.N		100.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	34.0N		26.0N		24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.05UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	11.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.17UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.9UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 9

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	115.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	6 00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	32.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	48.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	34.0N	26.0N	24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	747.NA	1.00MA
SUPPLY CURRENT	(ICC181)	10.3UA	1.00MA
SUPPLY CURRENT	(ICC280)	861.NA	1.00MA
SUPPLY CURRENT	(ICC281)	10.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		130.N		120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		130.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.27UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-136.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-948.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	234.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.04UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	79.4UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	85.9UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	90.8UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	76.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 9

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	40.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.94UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-427.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-446.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	430.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	492.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	438.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	387.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	501.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	329.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 10

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	20.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	20.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.69NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.04UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.24UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.08UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.91UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		130.N		105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		22.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		40.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	120.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	124.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	120.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	123.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	130.N	105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	24.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	64.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	63.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	61.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	62.0NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	135.N	120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	46.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 86.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.63UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-34.8NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-118.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	705.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.41UA	<*	500.NA
SUPPLY CURRENT	(ICC180)	28.1UA		1.00MA
SUPPLY CURRENT	(ICC181)	30.1UA		1.00MA
SUPPLY CURRENT	(ICC280)	29.4UA		1.00MA
SUPPLY CURRENT	(ICC281)	23.1UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MAS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 10

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		155.N		135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N		56.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N		54.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		155.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	92.0N	<	90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.37UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-220.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-229.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	252.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	280.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	158.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	165.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	169.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	127.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 11

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		24.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	5.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.69 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	18.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.02UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.30UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.13UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	826.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 11

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	200.N	130.N	105.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	32.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	52.0N	28.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N	30.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	11.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	16.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	130.N	105.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	32.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	66.0N	32.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N	30.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 116.N	< 90.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	5.00NA	1.00MA
SUPPLY CURRENT	(ICC181)	7.50NA	1.00MA
SUPPLY CURRENT	(ICC280)	7.50NA	1.00MA
SUPPLY CURRENT	(ICC281)	6.50NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		130.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.91UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-36.5NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-193.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	721.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.26UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	27.0UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	29.7UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	29.1UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	20.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 11

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)		160.N		135.N	125.N	250.NS
DATA SETUP TIME	(TDS)		14.0N		14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)		18.0N		20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)		52.0N		46.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)		26.0N		24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)		-4.00N		0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)		48.0N		42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)		160.N		135.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	<	88.0N	<	80.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)		26.0N		22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.24UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-131.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-148.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	130.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	145.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	173.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	179.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	186.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	131.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 12

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	95.0N	85.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	38.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	105.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	25.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	38.5PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.68UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.12UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.43UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.79UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	90.0N		80.0N		75.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		44.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N		14.0N		14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		40.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		16.0N		14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	29.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.28UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	542.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	69.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	90.0N	80.0N	70.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N	14.0N	14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	40.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	853.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	344.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	42.5NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT) -

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	95.0N	95.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.17UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-43.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-175.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	881.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.22UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	40.1UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	66.9UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	52.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	36.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 12

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N		105.N		100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		54.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-4.00N		0.00	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		48.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		125.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.68UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-200.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-240.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	238.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	272.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	245.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	312.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	281.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	209.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 13

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		22.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	31.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	192.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.16UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.70UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.88UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.73UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		135.N		110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	22.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	34.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.54UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.53UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		140.N		110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		36.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	56.0N		28.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		120.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 108.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.31UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.30UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.68UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-29.2NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-96.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.04UA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.60UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	26.9UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	33.3UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	33.7UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	28.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		145.N		130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		50.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		155.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.92UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-157.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-168.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	156.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	191.NA		500.NA
SUPPLY CURRENT	(ICC180)	160.UA		1.00MA
SUPPLY CURRENT	(ICC181)	183.UA		1.00MA
SUPPLY CURRENT	(ICC280)	177.UA		1.00MA
SUPPLY CURRENT	(ICC281)	139.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 14

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		145.N		125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		46.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		24.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	936.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.29UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	992.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.10UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 14

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	230.N		155.N		125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		28.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	808.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	415.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	88.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	416.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	92.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 14

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N	155.N	125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	54.0N	30.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 113.N	< 86.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	464.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	43.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	464.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	49.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	145.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.95UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-36.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-213.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	212.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.22UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	18.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	20.9UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	20.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	16.3UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 14

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	160.N	140.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	160.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 90.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	200.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.28UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-153.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-166.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	175.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	208.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	121.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	125.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	133.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	96.8UA		1.00MA

«* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 15

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	95.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	8.00N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	110.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.43UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.09UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.21UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.77UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	90.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	62.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	118.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	92.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	64.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	90.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N	6.00N	6.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	16.0N	14.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	47.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	73.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	61.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	49.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MNS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 85 C SN: 15

POST 1000 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	110.N	100.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	36.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	110.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.09UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-96.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-869.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	355.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.24UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	65.3UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	61.4UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	77.9UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	46.0UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 15

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	120.N		110.N		100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		40.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N		120.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.27UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-233.NA		500.NA
MAXIMUN INPUT CURRENT LOW	(IIL)	-243.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	250.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	294.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	380.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	334.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	441.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	269.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 16

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 992 DIAG = 928

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	155.N	125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N	32.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	538.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	600.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	697.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	708.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	463.NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	290.N	<*	160.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	84.0N	<*	38.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 140.N		< 86.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	27.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	31.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	28.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	28.0NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 16

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	295.N	<*	160.N		125.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	102.N	<*	40.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	200.N		135.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 157.N		< 88.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	21.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	23.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.0NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5Ø1Ø 1K CMOS STATIC RAM Ø9 FEB 78 TEMP: 85 C SN: 16

POST 1ØØØ HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = Ø

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	165.N	145.N	25Ø.NS
DATA SETUP TIME	(TDS)	16.ØN	18.ØN	22.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	2Ø.ØN	24.ØN	28.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	54.ØN	48.ØN	46.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	4Ø.ØN	3Ø.ØN	28.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-6.ØØN	-2.ØØN	4.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	48.ØN	42.ØN	34.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	2Ø5.N	16Ø.N	14Ø.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 1Ø4.N	< 88.ØN	< 84.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	28.ØN	24.ØN	22.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	16Ø.MV		4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	2.74UA	<*	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-17.6NA		5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-13Ø.NA		5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	6Ø5.NA	<*	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.46UA	<*	5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	17.8UA		1.ØØMA
SUPPLY CURRENT	(ICC1B1)	17.6UA		1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	2Ø.1UA		1.ØØMA
SUPPLY CUPRENT	(ICC2B1)	13.3UA		1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 16

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 2 DIAG = 384
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	230.N	185.N	165.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	18.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	34.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	48.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	225.N	180.N	155.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	< 98.0N	< 94.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	970.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-95.2NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-104.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	109.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	124.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	119.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	112.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	133.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	87.1UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 17

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	135.N	120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	46.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	135.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	308.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	558.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	664.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.13UA	1.00MA
SUPPLY CURPENT	(ICC2B1)	7.00UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	140.N	115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	46.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	9.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.12UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.15UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N		145.N		115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	6.00NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.77UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.75UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	140.N	125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.34UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-28.0NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-113.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	423.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.28UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	16.1UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	17.4UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	24.9UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	20.2UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 90.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.42UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-141.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-147.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	163.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	187.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	107.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	110.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	124.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	90.9UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 18

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	26.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-269.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.73NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.15UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.45UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.17UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.02UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 18

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	42.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	42.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	48.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	41.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	41.0NA	1.00MA

DEVICE PASSED ALL TESTS

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		130.N		105.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		14.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		48.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	29.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	31.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	28.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	29.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	130.N	120.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	18.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	52.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 88.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

QC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.90UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-40.6NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-87.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	526.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.58UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	24.4UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	28.6UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	25.2UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	20.5UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 18

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N	62.0N	56.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-10.0N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	56.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	< 98.0N	< 94.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.69UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-210.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-225.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	229.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	263.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	146.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	163.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	152.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	120.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MW5500ID 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 19

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	200.N		145.N		125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		30.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		140.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	86.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	346.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.92NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	605.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	611.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	687.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	458.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N <*	155.N	120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	68.0N	36.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	120.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 126.N	< 90.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	26.0NA	1.00MA
SUPPLY CURRENT	(ICC181)	27.5NA	1.00MA
SUPPLY CURRENT	(ICC280)	26.0NA	1.00MA
SUPPLY CURRENT	(ICC281)	27.0NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	260.N	<*	150.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	80.0N	<*	36.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 137.N	<	90.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.54NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	21.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	22.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	21.5NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
FAILED GALPAT (TIGHT LIMIT) ADD = 96 DIAG = 32

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N	155.N	135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	18.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	50.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	28.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N	155.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 88.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.67UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-37.0NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-267.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	764.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.86UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	19.5UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	18.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	22.1UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	14.2UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 19

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
FAILED NOISE IMMUNITY FUNCTIONAL ADD = 136 DIAG = 0
FAILED GALPAT (TIGHT LIMIT) ADD = 64 DIAG = 0

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N	175.N	155.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	18.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	22.0N	26.0N	30.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	30.0N	32.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N	170.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	< 96.0N	< 96.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	957.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-131.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-140.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	150.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	172.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	132.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	120.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	150.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	95.3UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 20

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		20.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	543.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	808.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	654.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	475.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 20

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	120.N	100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	24.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	24.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	23.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	19.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	17.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	120.N	100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	110.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	12.5NA	1.00MA
SUPPLY CURRENT	(ICC181)	14.0NA	1.00MA
SUPPLY CURRENT	(ICC280)	13.5NA	1.00MA
SUPPLY CURRENT	(ICC281)	11.0NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	933.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-106.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	183.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.16UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	15.3UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	18.3UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	17.0UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	12.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.42UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-91.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-96.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	96.4NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	111.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	103.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	113.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	113.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	82.6UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 21

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N	175.N	150.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	54.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	50.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N	160.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	< 88.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	38.0N	32.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	346.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	617.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	797.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	556.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	379.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 21

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N	175.N	140.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	48.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	28.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	46.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 108.N	< 86.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	22.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	28.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	12.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	10.0NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 21

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N <*	175.N	140.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	48.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	48.0N	30.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	145.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 114.N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.46NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	10.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	12.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.50NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.00NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		185.N		165.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		20.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N		56.0N		52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		28.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	66.0N		52.0N		44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		180.N		165.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	94.0N	<	92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	40.0N		36.0N		32.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	215.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.11UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-22.2NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-69.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	631.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.46UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	13.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	15.2UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	14.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	10.4UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 21

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		200.N		180.N		250.NS
DATA SETUP TIME	(TDS)	22.0N		18.0N		20.0N		50.0NS
DATA HOLD TIME	(TDH)	20.0N		24.0N		30.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	78.0N		70.0N		62.0N		90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		32.0N		34.0N		70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N		60.0NS
CE TO WRITE TIME	(TWS)	74.0N	<*	64.0N		56.0N		70.0NS
MIN READ CYCLE TIME	(TRC)	230.N		200.N		185.N		250.NS
MIN WRITE CYCLE TIME	(TWC)	< 119.N		< 112.N		< 106.N		220.NS
OUTPUT ENABLE TIME	(TEN)	44.0N		38.0N		34.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	240.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.80 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.04UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-110.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-152.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	131.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	163.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	88.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	93.0UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	94.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	69.1UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 22

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	155.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	32.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	36.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.12UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.88UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	470.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	468.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 22

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	265.N	<*	160.N		125.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	82.0N	<*	36.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		130.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 136.N		< 84.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	83.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	84.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	472.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	472.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 22

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	270.N	<*	155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	80.0N	<*	38.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 133.N		< 86.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	57.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	58.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	472.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	472.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 85 C SN: 22

POST 1000 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N		155.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	516.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-78.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-174.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	152.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	604.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	52.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	45.5UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	522.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	499.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5010 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 22

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	165.N	150.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	28.0N	30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	160.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 86.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.75UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-456.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-484.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	489.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	552.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	319.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	273.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	824.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	683.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 23

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	26.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	32.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.58NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-15.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	16.3NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	175.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.24UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.97UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 23

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	130.N	105.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	26.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	32.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	110.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	500.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	6.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	76.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.03UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	830.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.05UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 23

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		125.N		105.N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		38.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	6.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	69.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.96UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	721.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	8.97UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 85 C SN: 23

POST 1000 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.76UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-94.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-666.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	678.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.32UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	49.9UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	55.1UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	55.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	45.3UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 23

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIme	(TRC)	170.N		150.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.51UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-306.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-358.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	348.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	567.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	296.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	268.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	337.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	221.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 25

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	125.N	250.NS
DATA SETUP TIME	(TDS)	26.0N	20.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	50.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 88.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	82.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	154.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	500.PA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.09UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	15.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.39UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5010 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 25

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	18.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	48.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	91.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	4.61UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	217.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.45UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	20.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	48.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.46NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	33.0NA	1.00MA
SUPPLY CURRENT	(ICC181)	4.09UA	1.00MA
SUPPLY CURRENT	(ICC280)	97.5NA	1.00MA
SUPPLY CURRENT	(ICC281)	4.20UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		155.N		140.N	250.NS
DATA SETUP TIME	(TDS)	28.0N		24.0N		24.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	70.0N		62.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	66.0N		58.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N		165.N		150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N		< 98.0N		< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.24UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-16.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-42.0NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	527.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.04UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	53.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	99.5UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	59.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	70.1UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 25

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		175.N		160.N	250.NS
DATA SETUP TIME	(TDS)	28.0N		24.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	80.0N		72.0N		64.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		28.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-10.0N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	76.0N	<*	68.0N		60.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		190.N		175.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N		< 110.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		32.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	195.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.81 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.53UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-156.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-177.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	182.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	200.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	242.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	373.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	256.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	269.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 76 TEMP: 25 C SN: 26

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	120.N	105.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	346.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC180)	1.03UA	1.00MA
SUPPLY CURRENT	(ICC181)	1.62UA	1.00MA
SUPPLY CURRENT	(ICC280)	1.57UA	1.00MA
SUPPLY CURRENT	(ICC281)	1.05UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 26

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		125.N		100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	43.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	58.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	44.0NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 26

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		125.N		100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	46.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		16.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	20.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	33.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	27.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 85 C SN: 26

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		20.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		130.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.78UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-44.5NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-352.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	404.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.63UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	30.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	33.3UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	36.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	24.5UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 26

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		48.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.76UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-140.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-151.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	156.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	178.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	201.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	197.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	229.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	154.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 27

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	36.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	231.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.04NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.61UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.66UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.25UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.05UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	135.N	110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	170.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	171.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	572.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	569.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 27

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N	135.N	110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	731.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	42.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	43.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	439.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	436.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MW55001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 85 C SN: 27

POST 1000 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.79UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-27.2NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-204.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	725.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.49UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	36.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	36.3UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	24.7UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	17.9UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 27

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N	24.0N	28.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	50.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 86.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	894.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-120.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-126.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	135.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	156.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	173.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	167.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	146.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	99.5UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 28

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	145.N	125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	40.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	34.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	135.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.68 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.96NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	995.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.09UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.19UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	687.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 28

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N		155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	58.0N		30.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	135.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	42.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	133.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	31.5NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 28

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N		155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	68.0N		32.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 122.N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	962.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	113.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	28.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	116.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	24.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		145.N		130.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		46.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		145.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.85UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-54.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-431.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	580.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.92UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	27.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	27.6UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	31.7UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	20.6UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 28

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		160.N		145.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	20.0N		22.0N		26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		26.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		48.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	90.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	190.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.47UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-158.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-172.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	182.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	212.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	183.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	172.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	207.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	135.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 30

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	120.N	105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	20.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	353.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-577.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.7UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.00UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	8.03UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	115.N	100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	10.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	20.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	16.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	692.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.73NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC180)	7.96UA	1.00MA
SUPPLY CURRENT	(ICC181)	8.40UA	1.00MA
SUPPLY CURRENT	(ICC280)	259.NA	1.00MA
SUPPLY CURRENT	(ICC281)	272.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 30

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		115.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		22.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		36.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	6.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.49UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.73UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	136.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	137.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		50.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.20UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-29.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-77.5NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	830.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.12UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	89.4UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	138.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	85.0UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	91.9UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 30

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	52.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 90.0N	< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	14.3UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-210.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-245.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	241.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	298.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	375.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	532.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	372.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	377.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 31

POST 1000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N	32.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.5NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.54NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.50NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.19UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	19.6UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.47UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	19.2UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 31

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		120.N		100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		32.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	56.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	11.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	14.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.1UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		115.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	8.00N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	38.0N		32.0N		30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		24.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	36.0N		30.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.43 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.93 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC180)	42.5NA	1.00MA
SUPPLY CURRENT	(ICC181)	9.88UA	1.00MA
SUPPLY CURRENT	(ICC280)	5.00NA	1.00MA
SUPPLY CURRENT	(ICC281)	9.70UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	125.N	115.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	22.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	130.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.08UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-109.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-628.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	623.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.93UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	58.1UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	73.7UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	66.9UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	64.4UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5Ø1Ø 1K CMOS STATIC RAM Ø9 FEB 78 TEMP: 125 C SN: 31

POST 1ØØØ HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	16Ø.N	14Ø.N	13Ø.N	25Ø.NS
DATA SETUP TIME	(TDS)	12.ØN	12.ØN	14.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	2Ø.ØN	22.ØN	26.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	52.ØN	46.ØN	44.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	24.ØN	26.ØN	28.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN	2.ØØN	6.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	48.ØN	42.ØN	36.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	13Ø.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.ØN	< 82.ØN	< 82.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	28.ØN	24.ØN	22.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	1.67UA <*	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-417.NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-443.NA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	426.NA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	48Ø.NA	5ØØ.NA
SUPPLY CURRENT	(ICC1Ø)	35Ø.UA	1.ØØMA
SUPPLY CURRENT	(ICC1Ø1)	323.UA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø)	4Ø3.UA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø1)	273.UA	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 33

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		155.N		135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		46.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	21.0NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-308.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.96NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.50NA		500.NA
SUPPLY CURRENT	(ICC180)	6.18UA		1.00MA
SUPPLY CURRENT	(ICC181)	1.41MA	<*	1.00MA
SUPPLY CURRENT	(ICC280)	47.1UA		1.00MA
SUPPLY CURRENT	(ICC281)	1.47MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	155.N	130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.50NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.27NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	3.57UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.45MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	43.7UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.51MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N	155.N	125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	44.0N	26.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	40.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	120.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	885.PA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.42NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA		500.NA
SUPPLY CURRENT	(ICC1B0)	3.08UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.45MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	43.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.51MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N		175.N		160.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		50.0N		44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		150.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N		< 88.0N		< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.39UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-43.3NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-142.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	191.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	734.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	32.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.35MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	76.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.41MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 125 C SN: 33

POST 1000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	260.N	<*	225.N		205.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		58.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		26.0N		28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-10.0N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N		54.0N		48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		165.N		150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 104.N		< 94.0N		< 92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.48UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-250.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-262.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	282.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	314.NA		530.NA
SUPPLY CURRENT	(ICC1B0)	172.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.42MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	228.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.47MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

C-5

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 34

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		175.N		150.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	74.0N	<*	56.0N		54.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 132.N		< 110.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	339.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-654.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	149.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	160.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	193.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	194.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

C5

RCA MWS5Ø1D 1K CMOS STATIC RAM Ø9 FEB 78 TEMP: -4Ø C SN: 34

POST 1ØØØ HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.ØV		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	24Ø.N		18Ø.N		15Ø.N	25Ø.NS
DATA SETUP TIME	(TDS)	1Ø.ØN		1Ø.ØN		1Ø.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	14.ØN		18.ØN		2Ø.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	46.ØN		38.ØN		3Ø.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	94.ØN	<*	64.ØN		48.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN		Ø.ØØ		2.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	42.ØN		36.ØN		3Ø.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	135.N		11Ø.N		1ØØ.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 149.N	<	112.N	<	96.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	22.ØN		18.ØN		16.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	11Ø.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	12.ØNA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	769.PA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.5ØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.23NA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.ØØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	144.UA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	145.UA	1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	182.UA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	183.UA	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	250.N		180.N		150.N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	104.N	<*	68.0N		50.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 137.N	<	118.N	<	92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		18.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	923.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	146.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	146.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	182.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	183.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		185.N		165.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		16.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N		54.0N		48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N		66.0N		62.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		48.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		145.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 140.N	<	129.N	<	119.N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.31UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	93.2NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	416.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	1.77UA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	273.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	361.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	309.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	315.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N	<*	225.N		205.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	18.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N		62.0N		56.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	74.0N	<*	70.0N		68.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N		56.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		170.N		155.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 152.N		< 141.N		< 133.N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	13.5UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-246.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-265.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	269.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	303.NA		500.NA
SUPPLY CURRENT	(ICC180)	671.UA		1.00MA
SUPPLY CURRENT	(ICC181)	930.UA		1.00MA
SUPPLY CURRENT	(ICC280)	687.UA		1.00MA
SUPPLY CURRENT	(ICC281)	695.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: 25 C SN: 35

POST 1000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N		95.0N		90.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	14.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-76.9PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-1.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.69UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.66UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.45UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.35UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -40 C SN: 35

POST 1000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N	90.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N	8.00N	8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N	18.0N	16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	846.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.23NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	23.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	85.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	66.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	23.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 09 FEB 78 TEMP: -55 C SN: 35

POST 1000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N		85.0N		80.0N	250.NS
DATA SETUP TIME	(TDS)	10.0N		8.00N		8.00N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		38.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		16.0N		16.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	1.00NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.50NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.31NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.00NA	500.NA
SUPPLY CURRENT	(ICC1B0)	14.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	43.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	34.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N	105.N	100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	48.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	20.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	44.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	120.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.08UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-80.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-592.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	606.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	2.51UA	<*	500.NA
SUPPLY CURRENT	(ICC180)	49.4UA		1.00MA
SUPPLY CURRENT	(ICC181)	51.2UA		1.00MA
SUPPLY CURRENT	(ICC280)	58.9UA		1.00MA
SUPPLY CURRENT	(ICC281)	37.1UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	115.N	110.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	48.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	135.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 86.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.43UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-247.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-259.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	264.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	304.NA		500.NA
SUPPLY CURRENT	(ICC180)	301.UA		1.00MA
SUPPLY CURRENT	(ICC181)	286.UA		1.00MA
SUPPLY CURRENT	(ICC280)	346.UA		1.00MA
SUPPLY CURRENT	(ICC281)	224.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 2000-HOUR BURN-IN DATA

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RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 4

POST 2000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	105.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	22.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	8.00N	10.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	42.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N	14.0N	14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N	110.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	747.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	650.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.75NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.80NA	500.NA
SUPPLY CURRENT	(ICC1B0)	25.2UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	100.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	25.8UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	100.UA	1.00MA

DEVICE PASSED ALL TESTS

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RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -40 C SN: 4

POST 2000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N		95.0N		85.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	8.00N		10.0N		12.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N		12.0N		12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	25.3NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.12NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	842.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	990.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	60.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.00UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	69.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 4

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS).
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	120.N		95.0N		85.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	8.00N		10.0N		12.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		34.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N		12.0N		12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	80.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.3NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.23NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.15NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.06NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.00NA	500.NA
SUPPLY CURRENT	(ICC180)	427.NA	1.00MA
SUPPLY CURRENT	(ICC181)	59.1UA	1.00MA
SUPPLY CURRENT	(ICC280)	412.NA	1.00MA
SUPPLY CURRENT	(ICC281)	68.0UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 85 C SN: 4

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)			140.N		120.N	110.N	250.NS
DATA SETUP TIME	(TDS)			24.0N		20.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)			8.00N		12.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)			60.0N		52.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)			16.0N		16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)			-6.00N		-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)			60.0N		54.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)			150.N		130.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	<	86.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)			30.0N		26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.07UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-42.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-47.6NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	94.8NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	480.NA		500.NA
SUPPLY CURRENT	(ICC180)	228.UA		1.00MA
SUPPLY CURRENT	(ICC181)	415.UA		1.00MA
SUPPLY CURRENT	(ICC280)	226.UA		1.00MA
SUPPLY CURRENT	(ICC281)	322.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	22.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N	60.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	58.0N	52.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 88.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	23.6UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-276.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-288.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	300.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	353.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	795.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.23MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	781.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	906.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 3

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	48.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	130.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 60.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	69.2NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-5.06NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-6.30NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.38NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	7.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.27UA	1.00MA
SUPPLY CUPRENT	(ICC1B1)	4.25UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	145.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	144.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -40 C SN: 5

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		18.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		120.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.97NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	5.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.04NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	331.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	344.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	123.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	122.UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 5

POST 2000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		130.N		105.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		20.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.30NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.35NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	751.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.35NA	500.NA
SUPPLY CURRENT	(ICC1B0)	246.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	265.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	119.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	119.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 85 C SN: 5

POST 2000 HR BURN-IN PAGE 4 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	24.0N		20.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N		54.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N		54.0N		48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.14UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-60.7NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-74.9NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	121.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	429.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	51.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	62.5UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	213.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	202.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MW550010 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 5

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		155.N		140.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		20.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		60.0N		54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N		58.0N		52.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		155.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	102.N	<	94.0N	<	90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.20UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-386.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-415.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	394.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	442.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	275.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	313.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	461.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	403.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 6

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		160.N		130.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	42.0N		28.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		140.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.7NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.60NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.10NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	17.0UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	22.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	17.0UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.3UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	320.N	<*	160.N		135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		20.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	82.0N	<*	36.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	195.N		140.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 140.N		< 86.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-50.0PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.90NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.25NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	877.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.45NA	500.NA
SUPPLY CURRENT	(ICC1B0)	6.70UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	11.7UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.58UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.4UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 6

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	345.N	<*	185.N		135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	110.N	<*	42.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		42.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		140.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 170.N		< 92.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	700.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.22NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.65NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	354.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.25NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.97UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.86UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.95UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		44.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		155.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	215.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-24.5NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-33.4NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	49.3NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	275.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	51.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	58.9UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	54.2UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	51.9UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 6

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	160.N	140.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	52.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	50.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	160.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 86.0N	< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	32.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	185.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.29UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-151.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-157.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	168.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	202.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	197.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	203.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	213.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	163.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: /

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		125.N		115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		40.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.58 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.05NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-662.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.55NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.35NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.40NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.04UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	20.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.31UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	115.N	100.N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	36.0N	36.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	18.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.85NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-677.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.95NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.20NA	500.NA
SUPPLY CURRENT	(ICC1B0)	7.02NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.50NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.1UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	110.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	10.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	18.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TE')	22.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.94NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.40NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.02NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.70NA	500.NA
SUPPLY CURRENT	(ICC1B0)	-500.PA	1.00MA
SUPPLY CURRENT	(ICC1B1)	12.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	-2.00NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		140.N		130.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		18.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	301.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-45.5NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-54.6NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	79.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	219.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	62.6UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	75.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	71.6UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	67.3UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		160.N		150.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		50.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		48.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		155.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N		< 84.0N		< 82.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.98UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-308.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-562.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	333.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	377.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	374.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	335.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	425.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	282.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 8

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	38.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	5.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.30NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.57NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.53NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.80NA	500.NA
SUPPLY CURRENT	(ICC1B0)	14.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	14.4UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	260.N	<*	150.N		115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		14.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	66.0N		26.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 116.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.55NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.96NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	6.20NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.01NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.45NA	500.NA
SUPPLY CURRENT	(ICC1B0)	5.43UA	1.00MA
SUPPLY CUPRENT	(ICC1B1)	5.51UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.54UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.54UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	270.N	<*	150.N		115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	80.0N	<*	30.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 129.N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.50 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.25NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	758.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.55NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.11NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.35NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.34UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	4.40UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.41UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.47UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	135.N	120.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	42.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	135.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	196.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-11.1NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-35.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	66.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	298.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	42.0UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	42.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	44.1UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	38.4UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.53 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	911.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-102.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-114.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	117.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	133.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	142.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	137.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	153.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	114.UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 9

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		34.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		22.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		8.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		34.0N		28.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.7NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.83NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-5.55NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.28NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.55NA	500.NA
SUPPLY CURRENT	(ICC1B0)	6.40UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.09UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.0UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	120.N	100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	34.0N	34.0N	30.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00	4.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	38.0N	30.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.55NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.62NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	5.65NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	488.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.05NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.54UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	5.17UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.47UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.30UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)			175.N		115.N	95.0N	250.NS
DATA SETUP TIME	(TDS)			12.0N		10.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)			12.0N		14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)			36.0N		32.0N	26.0N	90.0NS
ADDRESS SETUP TIME	(TAS)			38.0N		22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)			0.00		4.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)			34.0N		34.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)			130.N		105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	<	84.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)		24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	300.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.03NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.17NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.65NA	500.NA
SUPPLY CURRENT	(ICC1B0)	966.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.99UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.05UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.22UA	1.00MA

DEVICE PASSED ALL TESTS

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	130.N	120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	42.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	130.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	304.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-72.9NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-79.3NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	102.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	313.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	83.7UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	84.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	94.9UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	71.6UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		150.N		135.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		16.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.89UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-469.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-494.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	464.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	530.NA	<*	500.NA
SUPPLY CURRENT	(ICC180)	466.UA		1.00MA
SUPPLY CURRENT	(ICC181)	408.UA		1.00MA
SUPPLY CURRENT	(ICC280)	530.UA		1.00MA
SUPPLY CURRENT	(ICC281)	340.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		20.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	20.8NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.06NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.75NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.47NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.16UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.25UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.19UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.91UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		125.N		105.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		18.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.85NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	1.49NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.07NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.70NA	500.NA
SUPPLY CURRENT	(ICC1B0)	386.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	365.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	384.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	355.NA	1.00MA

DEVICE PASSED ALL TESTS

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		125.N		105.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		20.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.40NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.31NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	508.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.25NA	500.NA
SUPPLY CURRENT	(ICC1B0)	228.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	218.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	233.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	212.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	135.N	110.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	22.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	52.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	484.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.5NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-45.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	51.9NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	128.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	30.6UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	32.8UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	52.3UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	25.7UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N	58.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	66.0N	58.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 90.0N	< 86.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.44UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-241.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-254.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	263.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	295.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	168.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	176.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	179.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	134.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 11

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	120.N	105.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	14.2NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-558.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.75NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.72NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	927.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.19UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.02UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	749.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		125.N		100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		34.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	48.0N		24.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.25NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	946.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.80NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.12NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.70NA	500.NA
SUPPLY CURRENT	(ICC1B0)	15.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	12.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	13.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.00NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 11

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		130.N		100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		34.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	60.0N		26.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.35NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.48NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	654.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.30NA	500.NA
SUPPLY CURRENT	(ICC1B0)	7.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.50NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	12.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.00NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	392.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-23.1NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-37.1NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	51.9NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	235.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	27.5UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	30.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	29.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	21.0UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	135.N	125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	48.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	135.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.54 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.28UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-142.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-156.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	130.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	150.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	178.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	184.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	190.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	133.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 12

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	95.0N	85.0N	80.0N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	42.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	10.0N	10.0N	12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	42.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	105.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.58 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	24.1NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.25NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.40NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.70NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.69UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.38UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.63UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.90UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	90.0N	80.0N	70.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	10.0N	10.0N	10.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	44.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	80.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.70NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	519.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.90NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	504.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	3.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	28.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.27UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	573.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	93.5NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 12

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	90.0N	80.0N	65.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	8.00N	10.0N	12.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	10.0N	10.0N	10.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	44.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N	20.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	80.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.58NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.60NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.01NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.30NA	500.NA
SUPPLY CURRENT	(ICC1B0)	17.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	869.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	361.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	63.0NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	95.0N	90.0N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	50.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	12.0N	14.0N	14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	48.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	110.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	604.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-31.3NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-40.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	95.4NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	438.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	39.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	67.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	52.0UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	35.7UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 12

POST 2000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N		105.N		100.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		54.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		54.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.73UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-230.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-238.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	237.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	265.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	245.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	315.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	281.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	208.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 13

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		18.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	31.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.19NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.60NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.75NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.95NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.08UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.60UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.68UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.51UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -40 C SN: 13

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	135.N	105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	32.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	20.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.85NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-515.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.10NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.90NA	500.NA
SUPPLY CURRENT	(ICC1B0)	22.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	36.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.44UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.44UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		135.N		105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	50.0N		22.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		36.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.65NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.21NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.35NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	819.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.80NA	500.NA
SUPPLY CURRENT	(ICC1B0)	10.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	20.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.22UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.23UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.63UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-28.6NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-45.6NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	55.6NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	124.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	26.7UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	33.1UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	33.5UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	27.8UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 13

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		140.N		130.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		50.0N		46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		20.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		50.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		155.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.93UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-164.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-174.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	152.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	187.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	163.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	186.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	180.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	140.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 14

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N		140.N		125.N	250.NS
DATA SETUP TIME	(TDS)	24.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		42.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		20.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		42.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	11.7NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	288.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	1.60NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.32NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	6.15UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.28UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	6.19UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.10UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		150.N		120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		44.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N		22.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	250.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-504.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.25NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.26NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.10NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.16UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	90.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	8.18UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	89.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 14

POST 2000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N		155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	48.0N		24.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 112.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.10NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.14NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.20NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.17NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.45NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.65UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	41.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	8.72UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	43.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		145.N		130.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		20.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		48.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		48.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		145.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N		30.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.04UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-53.1NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-109.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	46.7NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	238.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	23.5UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	21.6UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	25.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	16.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 14

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	155.N	140.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	18.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	54.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N	160.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 88.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	38.0N	32.0N	30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	190.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.80 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.28UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-167.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-175.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	181.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	211.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	130.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	130.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	142.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	100.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 15

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N		90.0N		85.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	12.0N		12.0N		14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	105.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.35NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.83NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.99NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.75NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.28UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.98UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	3.02UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.65UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N		85.0N		80.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	12.0N		10.0N		12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.15NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.71NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.04NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.40NA	500.NA
SUPPLY CURRENT	(ICC1B0)	56.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	109.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	85.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	62.5NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 15

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N		85.0N		80.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		10.0N		10.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	12.0N		10.0N		12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	0.00		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	22.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-204.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-2.15NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	365.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	44.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	77.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	62.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	52.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 85 C SN: 15

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	110.N		100.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N		14.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N		110.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	304.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-37.1NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-48.7NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	61.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	145.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	67.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	64.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	79.3UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	46.8UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 15

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	120.N		105.N		100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		44.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N		16.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		44.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N		120.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.10UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-255.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-266.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	263.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	303.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	396.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	351.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	454.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	276.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 16

POST 2000 HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N		150.N		125.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		140.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.55NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.15NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.65NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.44NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.60NA	500.NA
SUPPLY CURRENT	(ICC1B0)	580.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	669.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	673.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	445.NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MW5501D 1K CMOS STATIC RAM 03 APR 78 TEMP: -40 C SN: 16

POST 2000 HR BURN-IN PAGE 2 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	285.N	<*	160.N		125.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	78.0N	<*	34.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		42.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 133.N		< 86.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.80NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.69NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.65NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	823.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.65NA	500.NA
SUPPLY CURRENT	(ICC1B0)	21.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	26.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	21.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	28.0NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	310.N	<*	160.N		120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		36.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	96.0N	<*	36.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 152.N		< 82.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.87NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.10NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	496.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.10NA	500.NA
SUPPLY CURRENT	(ICC1B0)	15.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	22.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	16.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	25.0NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		165.N		145.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		22.0N		26.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		48.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N		26.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	200.N		160.N		140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	441.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-17.4NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-63.6NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	39.4NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	142.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	18.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.2UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	20.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 16

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N	185.N	165.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	22.0N	28.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N	54.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N	30.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	60.0N	54.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	220.N	180.N	155.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	< 94.0N	< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	940.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-106.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-115.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	114.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	124.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	125.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	118.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	140.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	91.9UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 17

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	18.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	42.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	42.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	130.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.15NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.51NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.10NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.72NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.55NA	500.NA
SUPPLY CURRENT	(ICC1B0)	571.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	701.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.05UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	6.91UA	1.00MA

DEVICE PASSED ALL TESTS

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	200.N	140.N	115.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	16.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	44.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	46.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	120.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC) <	96.0N <	80.0N <	80.0N <	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-300.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.53NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.60NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	931.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	19.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.02UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	5.00UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 17

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N		140.N		115.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		22.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		125.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.35NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.19NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.65NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	846.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	9.50NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	-500.PA	1.00MA
SUPPLY CURRENT	(ICC2B0)	4.63UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	4.65UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	135.N	125.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	20.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	50.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	18.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	50.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	404.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-22.6NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-34.9NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	36.6NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	93.3NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.7UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	25.4UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.8UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 17

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	56.0N	48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 88.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	32.0N	30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.81 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.51UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-153.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-166.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	167.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	188.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	112.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	117.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	128.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	96.6UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5Ø1Ø 1K CMOS STATIC RAM Ø3 APR 78 TEMP: 25 C SN: 18

POST 2ØØØ HR BURN-IN PAGE 1 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	22.ØN	22.ØN	2Ø.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	12.ØN	14.ØN	16.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	56.ØN	5Ø.ØN	42.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	2Ø.ØN	16.ØN	18.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN	Ø.ØØ	4.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	54.ØN	5Ø.ØN	42.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	15Ø.N	125.N	115.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.ØN	< 8Ø.ØN	< 8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	3Ø.ØN	26.ØN	24.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.68 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	23.7NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-4.Ø3NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.7ØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.1ØNA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.75NA	5ØØ.NA
SUPPLY CURRENT	(ICC1ØØ)	1.14UA	1.ØØMA
SUPPLY CURRENT	(ICC1Ø1)	1.44UA	1.ØØMA
SUPPLY CURRENT	(ICC2ØØ)	1.14UA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø1)	995.NA	1.ØØMA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	13Ø.N	1Ø5.N	25Ø.NS
DATA SETUP TIME	(TDS)	2Ø.ØN	18.ØN	16.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	12.ØN	14.ØN	18.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	54.ØN	46.ØN	42.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	26.ØN	18.ØN	16.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN	Ø.ØØ	4.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	56.ØN	46.ØN	42.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	14Ø.N	11Ø.N	1ØØ.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 9Ø.ØN	< 8Ø.ØN	< 8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	26.ØN	24.ØN	2Ø.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.ØMV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.4Ø V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.9Ø V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	3.65NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	2.97NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.Ø5NA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	931.PA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.2ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	49.5NA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	46.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	44.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	36.5NA	1.ØØMA

DEVICE PASSED ALL TESTS

RCA MWS5Ø41D 1K CMOS STATIC RAM Ø3 APR 78 TEMP: -55 C SN: 18

POST 2ØØØ HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	18Ø.N	13Ø.N	1Ø5.N	25Ø.NS
DATA SETUP TIME	(TDS)	22.ØN	18.ØN	16.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	12.ØN	14.ØN	16.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	56.ØN	46.ØN	42.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	3Ø.ØN	2Ø.ØN	18.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN	Ø.ØØ	4.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	5ó.ØN	46.ØN	42.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	145.N	11Ø.N	1ØØ.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.ØN	< 8Ø.ØN	< 8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	26.ØN	24.ØN	2Ø.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	9Ø.ØMV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.4Ø V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	4.15NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	2.55NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.5ØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.Ø5NA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.5ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	56.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	29.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	31.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	24.ØNA	1.ØØMA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		130.N		120.N	250.NS
DATA SETUP TIME	(TDS)	24.0N		22.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N		56.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N		56.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		28.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	140.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	488.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-30.2NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-44.1NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	71.5NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	345.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	23.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	28.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	24.5UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	20.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 18

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N		145.N		135.N	250.NS
DATA SETUP TIME	(TDS)	22.0N		22.0N		22.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N		60.0N		56.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N		62.0N		54.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		155.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	92.0N	<	90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.71UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-213.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-221.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	224.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	259.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	143.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	161.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	150.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	117.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 19

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	195.N		145.N		125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		26.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		46.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.60NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.30NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.20NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.75NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.10NA	500.NA
SUPPLY CURRENT	(ICC1B0)	609.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	609.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	680.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	447.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N		150.N		120.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	62.0N		30.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 119.N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.55NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.28NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.15NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	827.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.25NA	500.NA
SUPPLY CURRENT	(ICC1B0)	29.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	29.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	35.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	25.0NA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 19

POST 2000 HR BURN-IN PAGE 3 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N	<*	150.N		115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	74.0N	<*	32.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 132.N		< 86.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.05NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.67NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.10NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	685.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.55NA	500.NA
SUPPLY CURRENT	(ICC1B0)	15.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	14.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.0NA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	20.0N	26.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	18.0N	24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	50.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N	24.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	50.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	150.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 84.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	519.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-29.9NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-114.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	57.8NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	318.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	20.0UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.9UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	22.4UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.3UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	210.N	170.N	155.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	22.0N	26.0N	50.0NS
DATA HOLD TIME	(TDH)	16.0N	20.0N	26.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	62.0N	56.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	26.0N	28.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N	54.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	210.N	170.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 106.N	< 92.0N	< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	919.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-142.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-147.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	156.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	174.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	137.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	125.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	154.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	98.9UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5Ø010 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 20

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N	120.N	105.N	250.NS
DATA SETUP TIME	(TDS)	16.ØN	14.ØN	14.ØN	50.ØNS
DATA HOLD TIME	(TDH)	12.ØN	14.ØN	18.ØN	50.ØNS
WRITE PULSE WIDTH	(TWP)	44.ØN	40.ØN	36.ØN	90.ØNS
ADDRESS SETUP TIME	(TAS)	20.ØN	16.ØN	18.ØN	70.ØNS
ADDRESS HOLD TIME	(TAH)	-2.ØØN	2.ØØN	4.ØØN	60.ØNS
CE TO WRITE TIME	(TWS)	42.ØN	40.ØN	32.ØN	70.ØNS
MIN READ CYCLE TIME	(TRC)	135.N	115.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.ØN	< 80.ØN	< 80.ØN	220.NS
OUTPUT ENABLE TIME	(TEN)	28.ØN	24.ØN	22.ØN	60.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.05NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.19NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.85NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.52NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.05NA	500.NA
SUPPLY CURRENT	(ICC180)	539.NA	1.ØØMA
SUPPLY CURRENT	(ICC181)	794.NA	1.ØØMA
SUPPLY CURRENT	(ICC280)	648.NA	1.ØØMA
SUPPLY CURRENT	(ICC281)	470.NA	1.ØØMA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		120.N		100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		36.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		18.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.55NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.10NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.40NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	773.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.35NA	500.NA
SUPPLY CURRENT	(ICC1B0)	19.5MA	1.00MA
SUPPLY CURRENT	(ICC1B1)	24.0MA	1.00MA
SUPPLY CURRENT	(ICC2B0)	26.0MA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.5MA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	120.N	100.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	20.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.30NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.14NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.90NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	669.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.25NA	500.NA
SUPPLY CURRENT	(ICC1B0)	14.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	15.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	19.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.50NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	125.N	110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	458.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.5NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-57.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	32.4NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	187.NA	500.NA
SUPPLY CURRENT	(ICC180)	16.1UA	1.00MA
SUPPLY CURRENT	(ICC181)	19.3UA	1.00MA
SUPPLY CURRENT	(ICC280)	17.9UA	1.00MA
SUPPLY CURRENT	(ICC281)	13.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		130.N		125.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		50.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	82.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.44UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-101.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-112.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	102.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	120.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	110.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	121.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	120.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	88.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5Ø1D 1K CMOS STATIC RAM Ø3 APR 78 TEMP: 25 C SN: 21

POST 2ØØØ HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.ØV		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		175.N		150.N	25Ø.NS
DATA SETUP TIME	(TDS)	22.ØN		2Ø.ØN		2Ø.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	14.ØN		16.ØN		22.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	62.ØN		5Ø.ØN		44.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	26.ØN		2Ø.ØN		22.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-6.ØØN		Ø.ØØ		6.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	58.ØN		5Ø.ØN		42.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	195.N		16Ø.N		14Ø.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 98.ØN	<	8Ø.ØN	<	8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	4Ø.ØN		34.ØN		32.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	17Ø.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	Ø.25NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.17NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.Ø5NA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.Ø5NA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.8ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1ØØ)	616.NA	1.ØØMA
SUPPLY CURRENT	(ICC1Ø1)	795.NA	1.ØØMA
SUPPLY CURRENT	(ICC2ØØ)	544.NA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø1)	379.NA	1.ØØMA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.ØV	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N	175.N	14Ø.N	25Ø.NS
DATA SETUP TIME	(TDS)	2Ø.ØN	18.ØN	16.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	14.ØN	16.ØN	2Ø.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	54.ØN	5Ø.ØN	42.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	3Ø.ØN	24.ØN	22.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-6.ØØN	Ø.ØØ	6.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	58.ØN	5Ø.ØN	4Ø.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	19Ø.N	15Ø.N	125.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 1Ø2.N	< 84.ØN	< 8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	3Ø.ØN	32.ØN	28.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	14Ø.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	4.95NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	3.23NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.ØØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	788.PA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.3ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC18Ø)	27.5NA	1.ØØMA
SUPPLY CURRENT	(ICC181)	29.5NA	1.ØØMA
SUPPLY CURRENT	(ICC28Ø)	17.5NA	1.ØØMA
SUPPLY CURRENT	(ICC281)	6.5ØNA	1.ØØMA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

C-6

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.ØV		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N	<*	175.N		14Ø.N	25Ø.NS
DATA SETUP TIME	(TDS)	2Ø.ØN		16.ØN		16.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	14.ØN		16.ØN		2Ø.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	5Ø.ØN		48.ØN		42.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	46.ØN		26.ØN		24.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-6.ØØN		Ø.ØØ		6.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	58.ØN		46.ØN		4Ø.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	195.N		15Ø.N		12Ø.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 114.N	<	84.ØN	<	8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	36.ØN		3Ø.ØN		26.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	4.75NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	3.39NA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.7ØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	696.PA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.1ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	16.5NA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	16.5NA	1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	13.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	4.ØØNA	1.ØØMA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	225.N		185.N		165.N	250.NS
DATA SETUP TIME	(TDS)	24.0N		24.0N		24.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N		58.0N		52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	66.0N		60.0N		50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	205.N		180.N		160.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	<	92.0N	<	88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	44.0N		38.0N		34.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	205.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	636.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-22.7NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-45.3NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	28.0NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	94.7NA	500.NA
SUPPLY CURRENT	(ICC1B0)	14.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	15.1UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 21

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		200.N		185.N	250.NS
DATA SETUP TIME	(TDS)	26.0N		22.0N		24.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		20.0N		24.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	76.0N		68.0N		64.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		28.0N		30.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	78.0N	<*	68.0N		56.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	230.N		200.N		185.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 114.N		< 106.N		< 104.N	220.NS
OUTPUT ENABLE TIME	(TEN)	48.0N		42.0N		38.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	230.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.28 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.79 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.07UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-133.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-167.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	137.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	170.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	96.0UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	99.5UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	102.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	74.3UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

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PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N	155.N	130.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	40.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	40.0N	28.0N	26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	42.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 96.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.87 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.50NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-5.38NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-5.75NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.55NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	7.45NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.03UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.81UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	516.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	516.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N <*	110.N	125.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	74.0N <*	32.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 128.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.70NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.02NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.35NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.02NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.65NA	500.NA
SUPPLY CURRENT	(ICC1B0)	74.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	67.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	523.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	523.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	265.N <*	150.N	120.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	74.0N <*	32.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	34.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 128.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.65NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.98NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.35NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	992.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.75NA	500.NA
SUPPLY CURRENT	(ICC1B0)	51.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	47.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	522.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	522.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		145.N		130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		20.0N		22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		44.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	180.N		150.N		135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	493.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-69.6NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-92.5NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	152.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	421.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	53.4UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	46.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	568.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	544.UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		160.N		145.N	250.NS
DATA SETUP TIME	(TDS)	10.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		50.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		24.0N		26.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		48.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.66UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-477.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-508.NA	<*	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	506.NA	<*	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	560.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	527.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	281.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	876.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	731.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 23

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N	130.N	115.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	36.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N	22.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	120.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.00 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.10NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-4.77NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-14.7NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	13.4NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	143.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	4.03UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.86UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	11.8UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	140.N	125.N	105.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N	22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.47NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	5.84NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	72.0NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.96UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	778.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	8.97UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	125.N	100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N	22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N	36.0N	26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.20NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.05NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.60NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	4.95NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	58.5NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.05UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	10.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	709.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	9.03UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		130.N		120.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		135.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	201.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-46.7NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-65.2NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	145.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	450.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	46.5UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	53.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	51.0UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	43.0UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 23

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	145.N	135.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	46.0N	44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	145.N	135.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.32UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-294.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-323.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	325.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	500.NA	<*	500.NA
SUPPLY CURRENT	(ICC1B0)	275.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	253.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	311.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	204.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 25

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	140.N	125.N	250.NS
DATA SETUP TIME	(TDS)	30.0N	26.0N	24.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	50.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	18.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	54.0N	44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	140.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	74.7NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.70NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.02NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.75NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.79UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	16.9UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	5.02UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	13.6UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: -40 C SN: 25

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	135.N	115.N	250.NS
DATA SETUP TIME	(TDS)	24.0N	22.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N	50.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	48.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N	125.N	110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-700.PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.78NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.35NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	927.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.70NA	500.NA
SUPPLY CURRENT	(ICC1B0)	81.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	7.09UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	201.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	7.38UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		22.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		50.0N		42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	28.0N		20.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		50.0N		42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		125.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.70NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.36NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.60NA	500.NA
SUPPLY CURRENT	(ICC1B0)	38.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	6.48UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	98.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	6.82UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	155.N	140.N	250.NS
DATA SETUP TIME	(TDS)	32.0N	28.0N	28.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N	60.0N	56.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	70.0N	62.0N	54.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N	160.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 92.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	32.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	160.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.22UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-25.9NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-50.3NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	115.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	464.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	49.8UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	96.9UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	55.3UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	69.7UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V		LIMIT
ADDRESS ACCESS TIME	(TAA)	205.N		175.N		160.N		250.NS
DATA SETUP TIME	(TDS)	30.0N		28.0N		26.0N		50.0NS
DATA HOLD TIME	(TDH)	12.0N		16.0N		20.0N		50.0NS
WRITE PULSE WIDTH	(TWP)	80.0N		72.0N		66.0N		90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		24.0N		26.0N		70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N		-4.00N		2.00N		60.0NS
CE TO WRITE TIME	(TWS)	82.0N	<*	72.0N	<*	64.0N		70.0NS
MIN READ CYCLE TIME	(TRC)	210.N		185.N		170.N		250.NS
MIN WRITE CYCLE TIME	(TWC)	< 114.N		< 106.N		< 102.N		220.NS
OUTPUT ENABLE TIME	(TEN)	40.0N		34.0N		32.0N		60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	165.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.30 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.80 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.24UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-153.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-170.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	169.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	164.NA		500.NA
SUPPLY CURRENT	(ICC180)	227.UA		1.00MA
SUPPLY CURRENT	(ICC181)	556.UA		1.00MA
SUPPLY CURRENT	(ICC280)	240.UA		1.00MA
SUPPLY CURRENT	(ICC281)	258.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 26

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	42.0N		38.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		18.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.58 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.89 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.40NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.48NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.15NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.59NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.20NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.03UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	1.63UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	1.56UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.02UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	180.N	125.N	100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N	36.0N	32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	20.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	36.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.75NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.92NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	738.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.25NA	500.NA
SUPPLY CURRENT	(ICC1B0)	16.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	44.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	70.0NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	43.0NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.ØV		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	19Ø.N		125.N		1ØØ.N	25Ø.NS
DATA SETUP TIME	(TDS)	14.ØN		12.ØN		12.ØN	5Ø.ØNS
DATA HOLD TIME	(TDH)	1Ø.ØN		12.ØN		16.ØN	5Ø.ØNS
WRITE PULSE WIDTH	(TWP)	4Ø.ØN		36.ØN		32.ØN	9Ø.ØNS
ADDRESS SETUP TIME	(TAS)	42.ØN		22.ØN		18.ØN	7Ø.ØNS
ADDRESS HOLD TIME	(TAH)	-2.ØØN		2.ØØN		4.ØØN	6Ø.ØNS
CE TO WRITE TIME	(TWS)	4Ø.ØN		36.ØN		26.ØN	7Ø.ØNS
MIN READ CYCLE TIME	(TRC)	135.N		1Ø5.N		1ØØ.N	25Ø.NS
MIN WRITE CYCLE TIME	(TWC)	< 92.ØN	<	8Ø.ØN	<	8Ø.ØN	22Ø.NS
OUTPUT ENABLE TIME	(TEN)	24.ØN		2Ø.ØN		18.ØN	6Ø.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	9Ø.ØMV	4ØØ.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.6Ø V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.6Ø V
OUTPUT LEAKAGE CURRENT	(IOL)	5.Ø5NA	1.ØØUA
AVERAGE INPUT CURRENT LOW	(IIL)	3.4ØNA	5ØØ.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.ØØNA	5ØØ.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	65Ø.PA	5ØØ.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.3ØNA	5ØØ.NA
SUPPLY CURRENT	(ICC1BØ)	8.5ØNA	1.ØØMA
SUPPLY CURRENT	(ICC1B1)	2Ø.5NA	1.ØØMA
SUPPLY CURRENT	(ICC2BØ)	39.ØNA	1.ØØMA
SUPPLY CURRENT	(ICC2B1)	24.ØNA	1.ØØMA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N	120.N	110.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	16.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N	42.0N	38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	16.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	42.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N	125.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	716.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-20.2NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-53.2NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	57.3NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	259.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	28.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	31.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	34.1UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	22.7UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE ORIGINAL PAGE IS POOR

RCA MW55001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 2D

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		135.N		120.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		16.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		48.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 82.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.59UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-139.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-150.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	145.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	173.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	189.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	187.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	215.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	144.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 27

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		130.N		115.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		125.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.65NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.67NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.65NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.85NA	500.NA
SUPPLY CURRENT	(ICC1B0)	3.84UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	3.90UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.53UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	2.11UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N	130.N	110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N	12.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	16.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	38.0N	34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N	22.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N	38.0N	32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	115.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.60NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.00NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	781.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.10NA	500.NA
SUPPLY CURRENT	(ICC1B0)	192.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	191.NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	595.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	582.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	190.N		130.N		110.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		38.0N		34.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		22.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	44.0N		38.0N		32.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		115.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.70NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.80NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.80NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	800.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.30NA	500.NA
SUPPLY CURRENT	(ICC1B0)	55.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	53.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	464.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	453.NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	150.N		135.N		125.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		15.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N		26.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	165.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.0NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-44.7NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	65.7NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	200.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	36.1UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	36.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	23.6UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	17.1UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 27

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	170.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	18.0N	18.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N	18.0N	22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	50.0N	46.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	22.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	50.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	170.N	155.N	140.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	< 82.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	175.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	863.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-120.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-135.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	126.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	152.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	167.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	162.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	137.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	94.2UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 28

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N		145.N		120.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		18.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	30.0N		22.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		38.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N		130.N		115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 88.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	130.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	7.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.04NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.15NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.77NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.90NA	500.NA
SUPPLY CURRENT	(ICC180)	1.01UA	1.00MA
SUPPLY CURRENT	(ICC181)	1.07UA	1.00MA
SUPPLY CURRENT	(ICC280)	1.19UA	1.00MA
SUPPLY CURRENT	(ICC281)	677.NA	1.00MA

DEVICE PASSED ALL TESTS

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	235.N	150.N	120.N	250.NS
DATA SETUP TIME	(TDS)	15.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	56.0N	26.0N	20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	38.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	165.N	125.N	105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 110.N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	4.90NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.20NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	685.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.30NA	500.NA
SUPPLY CURRENT	(ICC1B0)	136.NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	44.0NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	142.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	30.0NA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5Ø01D 1K CMOS STATIC RAM 03 APR 78 TEMP: -55 C SN: 28

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	245.N		155.N		120.N	250.NS
DATA SETUP TIME	(TDS)	16.ØN		14.ØN		14.ØN	50.ØNS
DATA HOLD TIME	(TDH)	12.ØN		14.ØN		18.ØN	50.ØNS
WRITE PULSE WIDTH	(TWP)	44.ØN		40.ØN		36.ØN	90.ØNS
ADDRESS SETUP TIME	(TAS)	64.ØN		26.ØN		22.ØN	70.ØNS
ADDRESS HOLD TIME	(TAH)	-4.ØØN		Ø.ØØ		4.ØØN	60.ØNS
CE TO WRITE TIME	(TWS)	46.ØN		38.ØN		34.ØN	70.ØNS
MIN READ CYCLE TIME	(TRC)	175.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 118.N	<	80.ØN	<	80.ØN	220.NS
OUTPUT ENABLE TIME	(TEN)	28.ØN		24.ØN		22.ØN	60.ØNS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.30NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.64NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.80NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	858.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.40NA	500.NA
SUPPLY CURRENT	(ICC1Ø)	112.NA	1.ØØMA
SUPPLY CURRENT	(ICC1Ø1)	30.5NA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø)	116.NA	1.ØØMA
SUPPLY CURRENT	(ICC2Ø1)	22.5NA	1.ØØMA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	145.N	130.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	20.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	16.0N	20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	44.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N	46.0N	38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	145.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	363.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-19.0NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-37.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	63.0NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	206.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	26.3UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	26.3UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	30.0UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	19.4UA	1.00MA

DEVICE PASSED ALL TESTS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 28

POST 2000 HR BURN-IN PAGE 5 OF 5

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	185.N		155.N		140.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N		52.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N		52.0N		46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	185.N		160.N		145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N	<	84.0N	<	84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		32.0N		28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	180.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.30UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-156.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-174.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	169.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	196.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	175.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	163.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	196.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	127.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 30

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N		120.N		105.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N		42.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	115.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	364.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	235.PA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	2.05NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.62NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	12.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	18.5UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	7.28UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	8.71UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N	115.N	100.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	40.0N	36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N	40.0N	34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.75NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.34NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.25NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	692.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.35NA	500.NA
SUPPLY CURRENT	(ICC1B0)	7.80UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.34UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	220.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	233.NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		115.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	16.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N		16.0N		16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	135.N		110.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.90NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.35NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.25NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	569.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.35NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.60UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	8.84UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	102.NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	94.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		130.N		120.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		18.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N		50.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		50.0N		44.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		135.N		125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N		< 80.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	135.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.83UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-38.4NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-59.3NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	67.3NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	167.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	87.4UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	136.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	82.8UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	91.9UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	175.N	150.N	135.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	64.0N	58.0N	52.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N	20.0N	22.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	64.0N	58.0N	50.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N	155.N	145.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	< 88.0N	< 84.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N	30.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	155.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.83 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	14.4UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-223.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-242.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	223.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	273.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	361.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	523.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	359.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	373.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 31

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT) .

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		125.N		110.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		16.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		36.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	26.0N		20.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		8.00N	60.0NS
CE TO WRITE TIME	(TWS)	42.0N		38.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	105.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.39 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	9.80NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-4.29NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-6.70NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	3.08NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.45NA	500.NA
SUPPLY CURRENT	(ICC1B0)	2.21UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	24.0UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.45UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	23.7UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	165.N	120.N	100.N	250.NS
DATA SETUP TIME	(TDS)	12.0N	12.0N	12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	36.0N	32.0N	28.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	34.0N	20.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N	2.00N	6.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N	34.0N	30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	120.N	100.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N	22.0N	20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-1.95NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.96NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	946.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.45NA	500.NA
SUPPLY CURRENT	(ICC1B0)	64.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	14.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	8.50NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	14.4UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	155.N		110.N		95.0N	250.NS
DATA SETUP TIME	(TDS)	12.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	40.0N		34.0N		32.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	36.0N		20.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	40.0N		34.0N		26.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	125.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 86.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.42 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.92 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-2.25NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-3.03NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.40NA	530.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.40NA	500.NA
SUPPLY CURRENT	(ICC1B0)	41.5NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	13.1UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	-1.00NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	12.9UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	145.N		125.N		115.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		16.0N		20.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		130.N		120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.36 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.86 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	240.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-65.2NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-95.9NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	120.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	361.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	55.8UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	76.9UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	64.1UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	67.0UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	160.N		140.N		130.N	250.NS
DATA SETUP TIME	(TDS)	16.0N		16.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	14.0N		18.0N		22.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N		46.0N		44.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		22.0N		24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		2.00N		6.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		46.0N		40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		140.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	1.49UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-408.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-450.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	412.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	471.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	334.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	318.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	383.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	265.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 35

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	200.N	160.N	140.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	18.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N	44.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	22.0N	16.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N	46.0N	40.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	135.N	120.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.37 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	19.7NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.91NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.90NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.42NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.95NA		500.NA
SUPPLY CURRENT	(ICC1B0)	15.6UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.44MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	51.2UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.51MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		155.N		130.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	52.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	32.0N		20.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	54.0N		46.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	155.N		115.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 94.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.75NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.66NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	4.00NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	673.PA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.30NA		500.NA
SUPPLY CURRENT	(ICC1B0)	13.2UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.48MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	48.4UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.56MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		155.N		130.N	250.NS
DATA SETUP TIME	(TDS)	20.0N		16.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	54.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	38.0N		22.0N		18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	56.0N		46.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N		120.N		105.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 102.N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N		24.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	100.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-350.PA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.47NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.45NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	854.PA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.50NA		500.NA
SUPPLY CURRENT	(ICC1B0)	12.0UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.49MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	47.6UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.56MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N		185.N		170.N	250.NS
DATA SETUP TIME	(TDS)	24.0N		22.0N		20.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		14.0N		18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	60.0N		54.0N		50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	20.0N		18.0N		20.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N		-2.00N		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	62.0N		54.0N		48.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	175.N		145.N		130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 90.0N		< 82.0N		< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	34.0N		30.0N		26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	150.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.54 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	390.NA		1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-53.6NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-62.1NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	112.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	332.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	39.9UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.36MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	79.0UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.44MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	280.N <*	240.N	220.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	66.0N	60.0N	54.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	24.0N	24.0N	24.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	66.0N	58.0N	52.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	160.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 100.N	< 94.0N	< 88.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	32.0N	30.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.23UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-242.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-262.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	269.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	297.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	172.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	1.44MA	<*	1.00MA
SUPPLY CURRENT	(ICC2B0)	223.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	1.52MA	<*	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 34

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	215.N		175.N		150.N	250.NS
DATA SETUP TIME	(TDS)	18.0N		16.0N		18.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	48.0N		44.0N		40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	72.0N	<*	54.0N		50.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N		0.00		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	50.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	150.N		120.N		110.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 129.N		< 108.N		< 100.N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N		26.0N		22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	120.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.58 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	313.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-4.52NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.85NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.83NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	6.50NA	500.NA
SUPPLY CURRENT	(ICC1B0)	162.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	175.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	213.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	214.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	240.N		180.N		145.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	90.0N	<*	58.0N		44.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		34.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 144.N		< 108.N		< 90.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	20.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.90 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.10NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-2.98NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.40NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.15NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.20NA	500.NA
SUPPLY CURRENT	(ICC1B0)	160.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	160.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	206.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	206.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	250.N		180.N		145.N	250.NS
DATA SETUP TIME	(TDS)	14.0N		14.0N		14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N		40.0N		36.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	102.N	<*	64.0N		46.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		2.00N		4.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		40.0N		30.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	140.N		105.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 155.N	<	114.N	<	92.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		20.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	95.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	8.75NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	3.30NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.70NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	796.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.20NA	500.NA
SUPPLY CURRENT	(ICC1B0)	162.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	162.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	207.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	207.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	220.N	180.N	165.N	250.NS
DATA SETUP TIME	(TDS)	20.0N	18.0N	20.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	58.0N	52.0N	48.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	66.0N	60.0N	58.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	58.0N	52.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	160.N	140.N	130.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 153.N	< 121.N	< 116.N	220.NS
OUTPUT ENABLE TIME	(TEN)	32.0N	28.0N	26.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.34 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.84 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	5.29UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-37.2NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-68.9NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	140.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	420.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	280.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	371.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	319.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	326.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS50010 1K CMOS STATIC RAM 03 APR 78 TEMP: 125 C SN: 34

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	255.N <*	215.N	200.N	250.NS
DATA SETUP TIME	(TDS)	22.0N	20.0N	22.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	18.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	68.0N	60.0N	56.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	70.0N	66.0N	64.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-8.00N	-4.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	68.0N	60.0N	54.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	190.N	165.N	150.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 148.N	< 136.N	< 129.N	220.NS
OUTPUT ENABLE TIME	(TEN)	36.0N	32.0N	28.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	170.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.32 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	12.8UA <*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-243.NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-271.NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	248.NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	280.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	662.UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	919.UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	678.UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	685.UA	1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

RCA MWS5001D 1K CMOS STATIC RAM 03 APR 78 TEMP: 25 C SN: 35

POST 2000 HR BURN-IN

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	105.N	95.0N	85.0N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	14.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	44.0N	42.0N	40.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	14.0N	14.0N	14.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	0.00	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	48.0N	40.0N	36.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	115.N	105.N	100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	26.0N	24.0N	22.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	110.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.38 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.88 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	10.0NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-4.34NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-4.75NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	2.19NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	5.65NA	500.NA
SUPPLY CURRENT	(ICC1B0)	1.74UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	2.71UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	2.51UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	1.37UA	1.00MA

DEVICE PASSED ALL TESTS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N		85.0N		80.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N		14.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	10.0N		10.0N		12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		22.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	90.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.40 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	3.00NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	2.20NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	3.45NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	1.00NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.25NA	500.NA
SUPPLY CURRENT	(ICC1B0)	31.0NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	84.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	74.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	19.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V		5.0V		5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	100.N		85.0N		80.0N	250.NS
DATA SETUP TIME	(TDS)	14.0N		12.0N		12.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N		12.0N		14.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	46.0N		42.0N		38.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	10.0N		10.0N		12.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-2.00N		0.00		2.00N	60.0NS
CE TO WRITE TIME	(TWS)	46.0N		42.0N		38.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	100.N		100.N		100.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	<	80.0N	<	80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	24.0N		20.0N		18.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	85.0MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.41 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.91 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	-50.0PA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-1.90NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-3.20NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	442.PA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	4.15NA	500.NA
SUPPLY CURRENT	(ICC1B0)	8.00NA	1.00MA
SUPPLY CURRENT	(ICC1B1)	41.5NA	1.00MA
SUPPLY CURRENT	(ICC2B0)	30.5NA	1.00MA
SUPPLY CURRENT	(ICC2B1)	17.5NA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	115.N	105.N	95.0N	250.NS
DATA SETUP TIME	(TDS)	18.0N	14.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	10.0N	12.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	50.0N	46.0N	42.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	16.0N	16.0N	16.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-4.00N	-2.00N	2.00N	60.0NS
CE TO WRITE TIME	(TWS)	52.0N	46.0N	42.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	130.N	120.N	115.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 80.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	28.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA	LIMIT
OUTPUT VOLTAGE LOW	(VOL)	125.MV	400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.35 V	3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.85 V	4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	690.NA	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-53.5NA	500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-53.0NA	500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	80.9NA	500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	216.NA	500.NA
SUPPLY CURRENT	(ICC1B0)	46.0UA	1.00MA
SUPPLY CURRENT	(ICC1B1)	48.4UA	1.00MA
SUPPLY CURRENT	(ICC2B0)	54.8UA	1.00MA
SUPPLY CURRENT	(ICC2B1)	34.2UA	1.00MA

DEVICE PASSED ALL TESTS

PASSED GALPAT (WIDE LIMITS)
PASSED NOISE IMMUNITY FUNCTIONAL
PASSED GALPAT (TIGHT LIMIT)

		VCC = 4.5V	5.0V	5.5V	LIMIT
ADDRESS ACCESS TIME	(TAA)	125.N	115.N	105.N	250.NS
DATA SETUP TIME	(TDS)	16.0N	16.0N	16.0N	50.0NS
DATA HOLD TIME	(TDH)	12.0N	14.0N	16.0N	50.0NS
WRITE PULSE WIDTH	(TWP)	56.0N	52.0N	50.0N	90.0NS
ADDRESS SETUP TIME	(TAS)	18.0N	18.0N	18.0N	70.0NS
ADDRESS HOLD TIME	(TAH)	-6.00N	-2.00N	0.00	60.0NS
CE TO WRITE TIME	(TWS)	56.0N	50.0N	46.0N	70.0NS
MIN READ CYCLE TIME	(TRC)	145.N	135.N	125.N	250.NS
MIN WRITE CYCLE TIME	(TWC)	< 84.0N	< 80.0N	< 80.0N	220.NS
OUTPUT ENABLE TIME	(TEN)	30.0N	26.0N	24.0N	60.0NS

DC PARAMETRIC MEASUREMENTS :

		DATA		LIMIT
OUTPUT VOLTAGE LOW	(VOL)	145.MV		400.MV
OUTPUT VOLTAGE HIGH	(VOH1)	4.33 V		3.60 V
OUTPUT VOLTAGE HIGH	(VOH2)	4.82 V		4.60 V
OUTPUT LEAKAGE CURRENT	(IOL)	2.15UA	<*	1.00UA
AVERAGE INPUT CURRENT LOW	(IIL)	-239.NA		500.NA
MAXIMUM INPUT CURRENT LOW	(IIL)	-255.NA		500.NA
AVERAGE INPUT CURRENT HIGH	(IIH)	243.NA		500.NA
MAXIMUM INPUT CURRENT HIGH	(IIH)	286.NA		500.NA
SUPPLY CURRENT	(ICC1B0)	281.UA		1.00MA
SUPPLY CURRENT	(ICC1B1)	269.UA		1.00MA
SUPPLY CURRENT	(ICC2B0)	321.UA		1.00MA
SUPPLY CURRENT	(ICC2B1)	207.UA		1.00MA

<* MEASURED VALUE OUTSIDE SPECIFIED LIMITS

REPRODUCIBILITY OF THE
ORIGINAL PAGE IS POOR